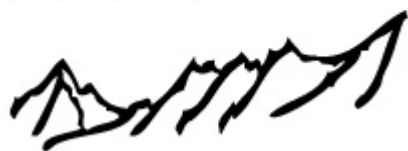




ÉCOLE DE PHYSIQUE
des HOUCHES



FEATURES OF THE INSULATOR CLOSE TO THE SUPERCONDUCTOR-INSULATOR TRANSITION

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Laboratoire de Physique
des 2 Infinis

People



Le Hong Hoàng
To



Shamashis
Sengupta



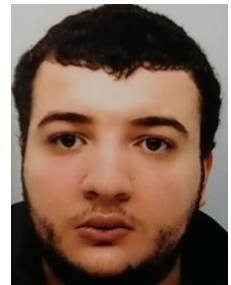
Laurent
Bergé



Louis
Dumoulin



Grégoire
Dabancourt-Thebaud



Adam
Bouheddou



Miguel Ortuño



Andrés M. Somoza



Vincent Humbert

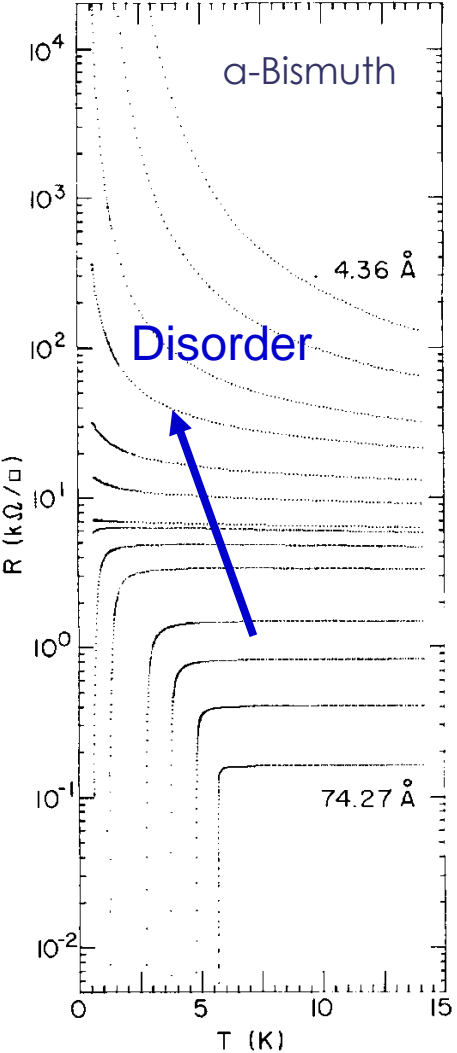
Financed by :



Motivation

Superconductor-Insulator Transitions

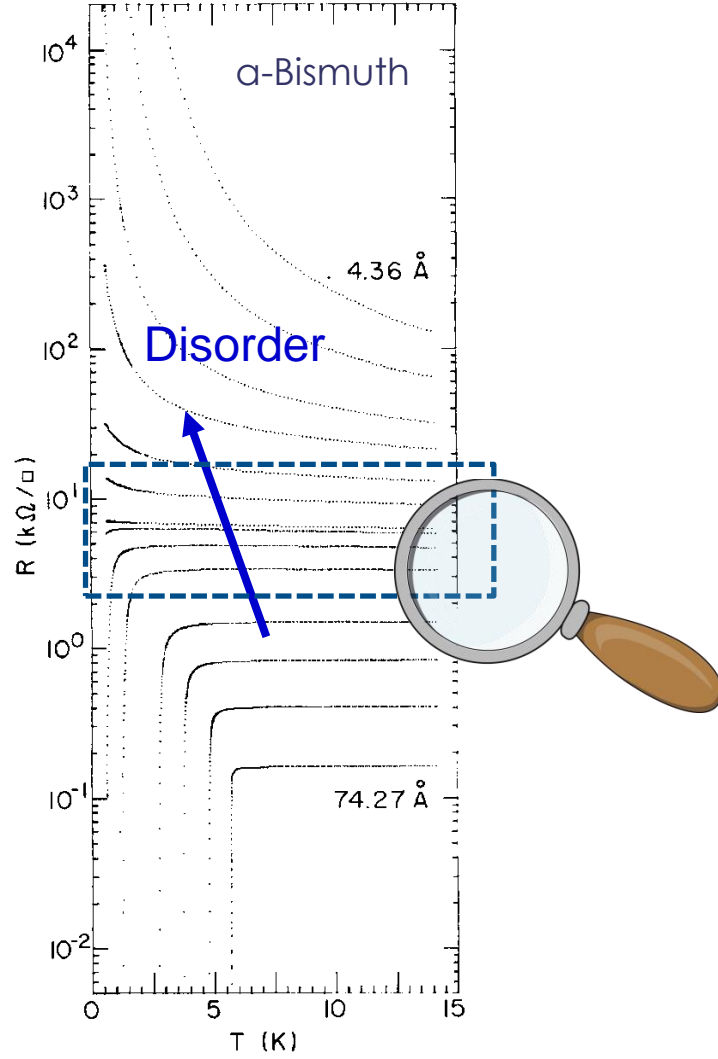
Haviland et al, PRL 62 18 1989



Superconductor-Insulator Transitions

Disorder-induced transition

Haviland et al, PRL 62 18 1989



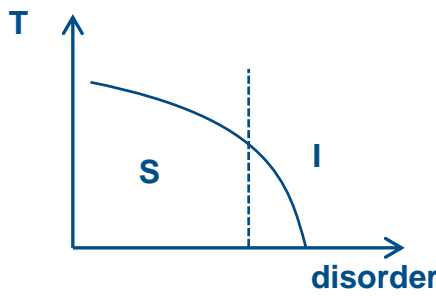
Disorder-induced SIT in 2D systems

Bosonic scenarii

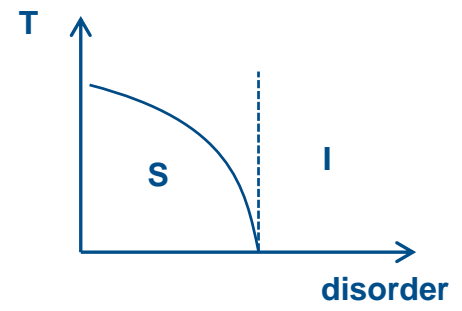
Fermionic scenarii

Cooper pairs in the insulator

NO Cooper pairs in the insulator



Fisher, *Phys. Rev. Lett.*, **65** 7 1990

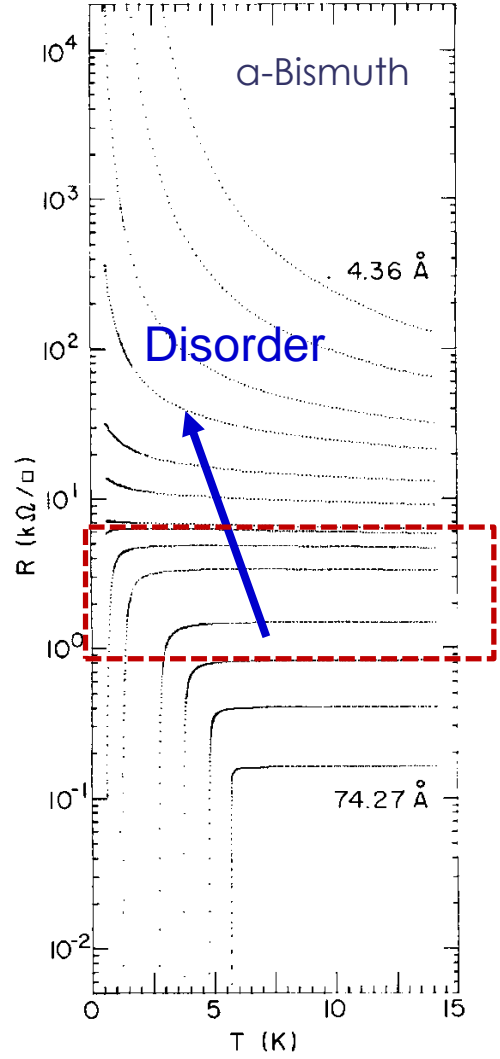


Finkel'stein, *JETP Letters*, **45** 46 (1987)

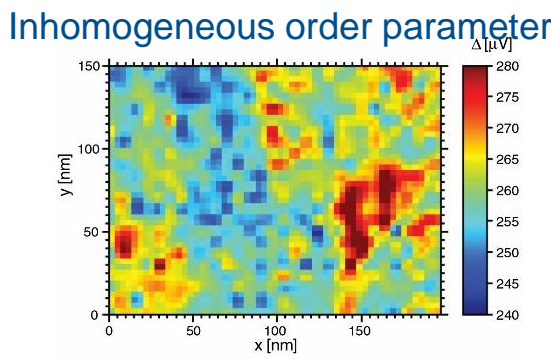
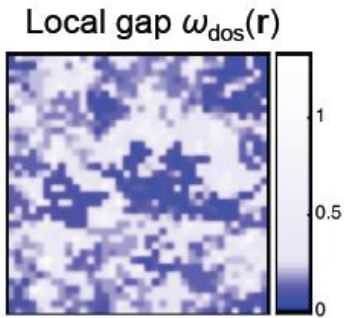
Superconductor-Insulator Transitions

Electronic inhomogeneities

Haviland et al, PRL 62 18 1989

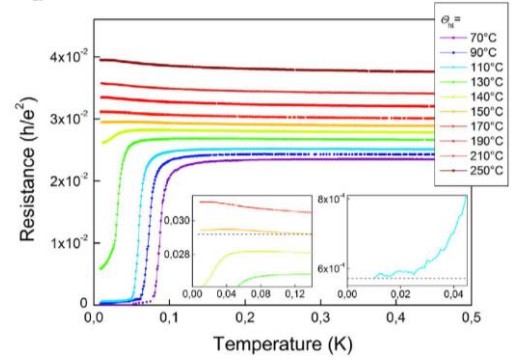
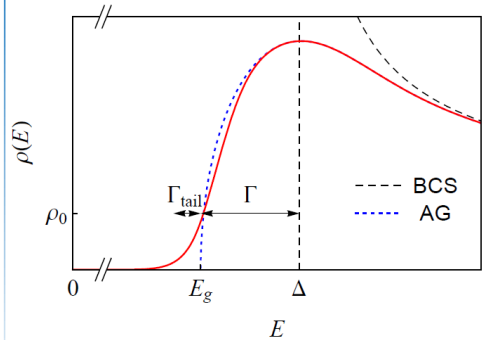


Superconducting side



Bouadim et al., *Nat. Phys.*, 7 884 2011

Sacépé et al., *PRL*, 101 157006 2008

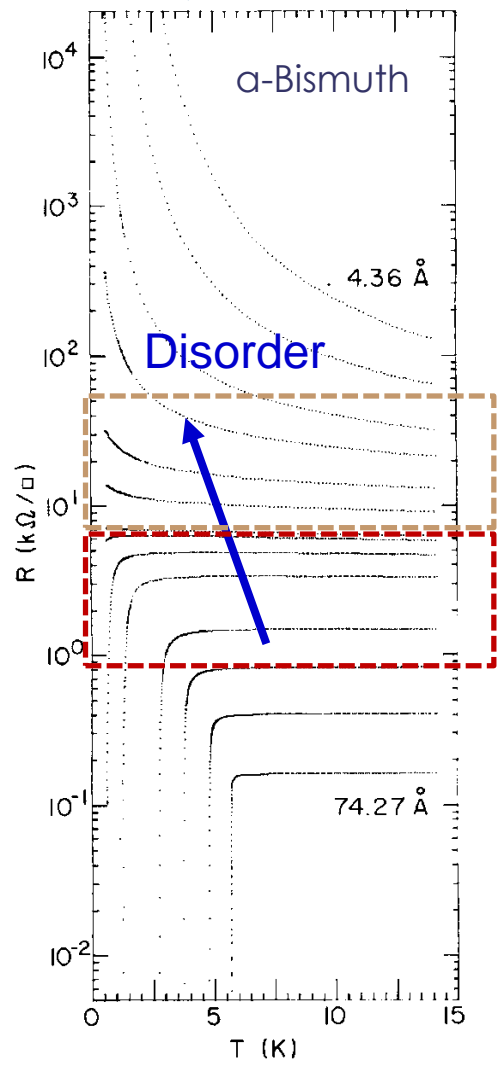


Skvortsov & Feigel'man, *JETP*, 117, 487 2013 Couëdo et al., *Sci. Rep.*, 6 35824 2016

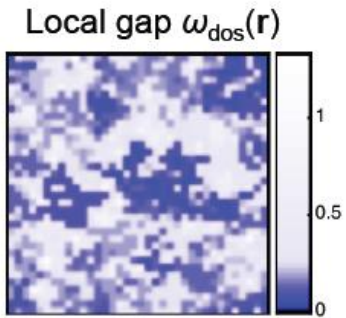
Superconductor-Insulator Transitions

Electronic inhomogeneities

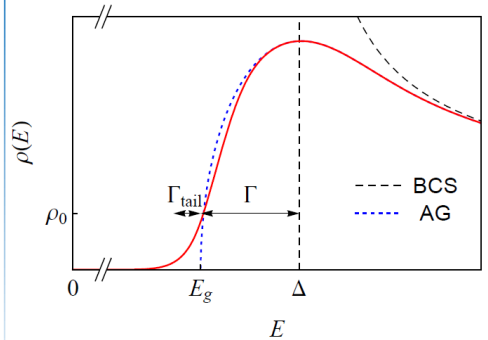
Haviland et al, PRL 62 18 1989



Superconducting side

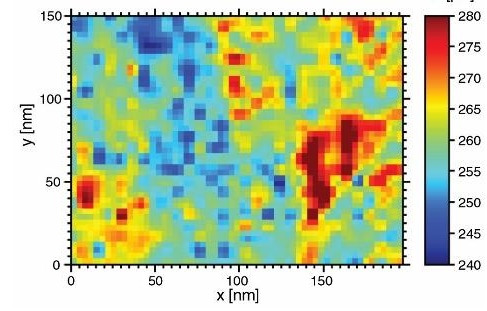


Bouadim et al., Nat. Phys., 7 884 2011

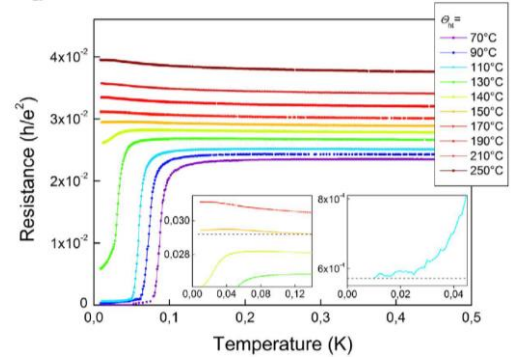


Skvortsov & Feigel'man, JETP, 117, 487 2013

Inhomogeneous order parameter



Sacépé et al., PRL, 101 157006 2008



Couëdo et al., Sci. Rep., 6 35824 2016

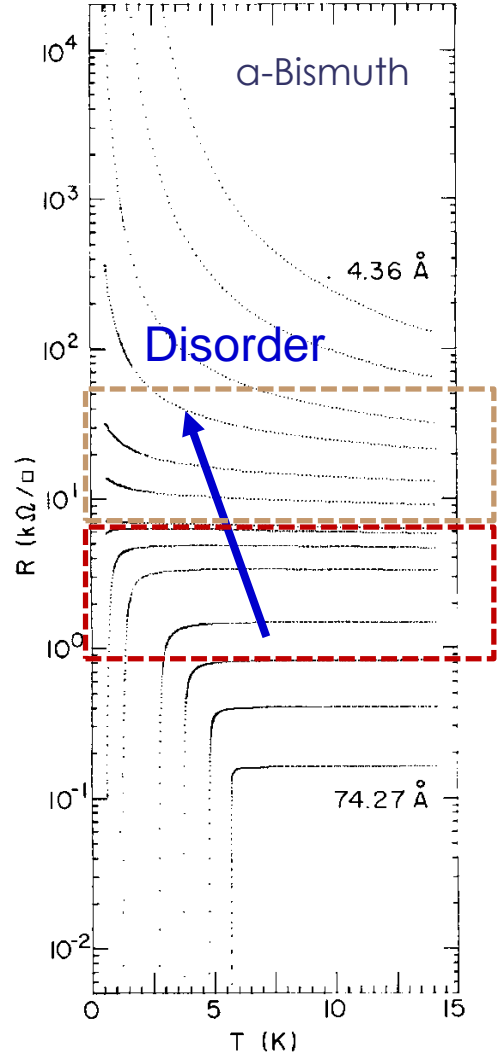
Insulating side

- ✓ Homogeneous phase ?
- ✓ Superconducting grains ?
- ✓ Influence on electronic transport ?

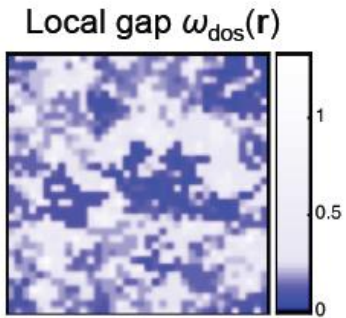
Superconductor-Insulator Transitions

Electronic inhomogeneities

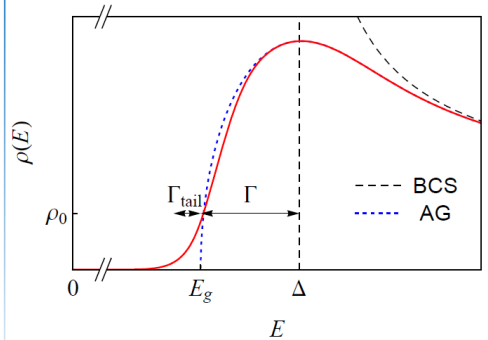
Haviland et al, PRL 62 18 1989



Superconducting side

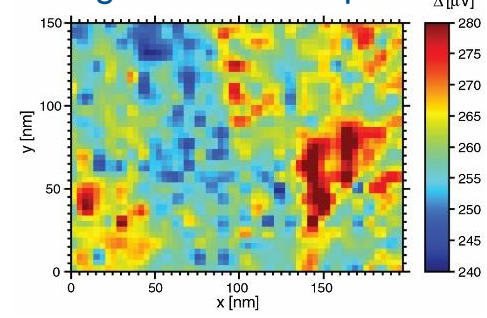


Bouadim et al., Nat. Phys., 7 884 2011

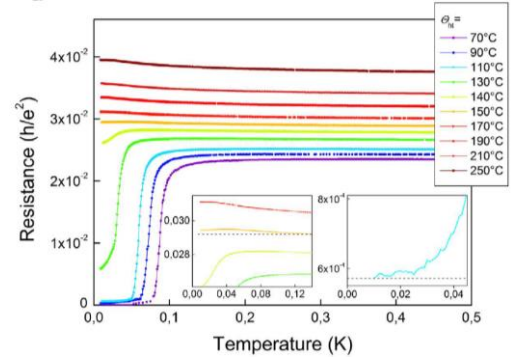


Skvortsov & Feigel'man, JETP, 117, 487 2013

Inhomogeneous order parameter



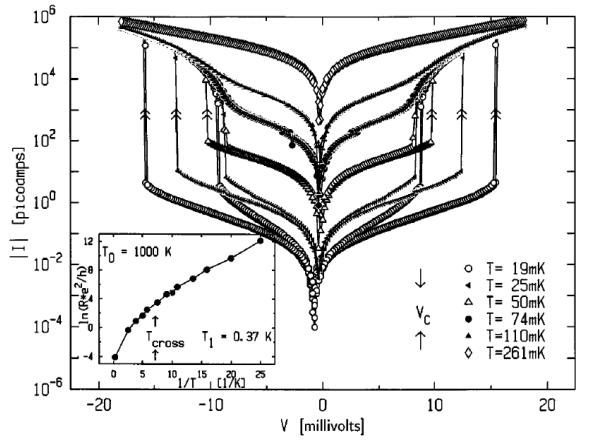
Sacépé et al., PRL, 101 157006 2008



Couëdo et al., Sci. Rep., 6 35824 2016

Insulating side

- ✓ Homogeneous phase ?
- ✓ Superconducting grains ?
- ✓ Influence on electronic transport ?



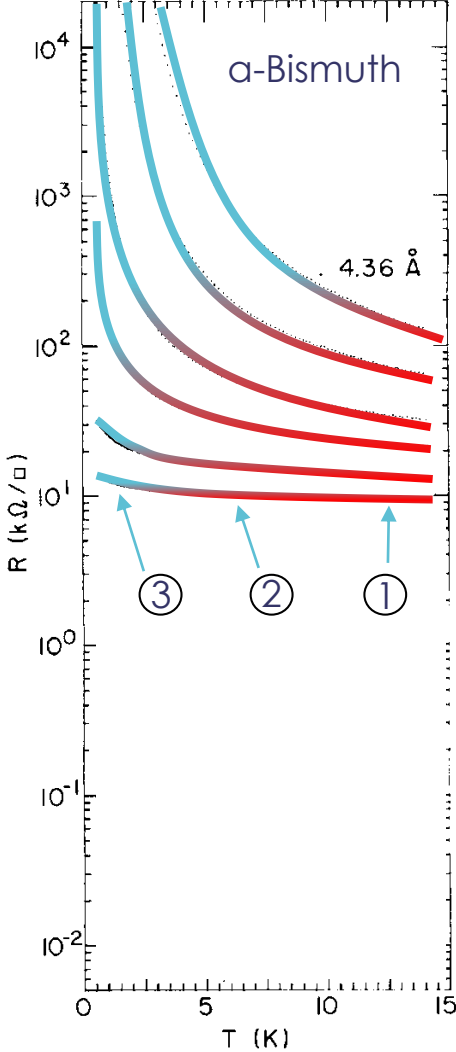
Ladieu et al., PRB, 53 973 1996
 Sambandamurthy et al., PRL 94, 017003 (2005)
 Fistul et al., PRL 100, 086805 (2008)
 Vinokur et al., Nature 452, 613 (2008)
 Ovadia et al., PRL 102, 176802 (2009)

ACTIVATED ELECTRONIC TRANSPORT

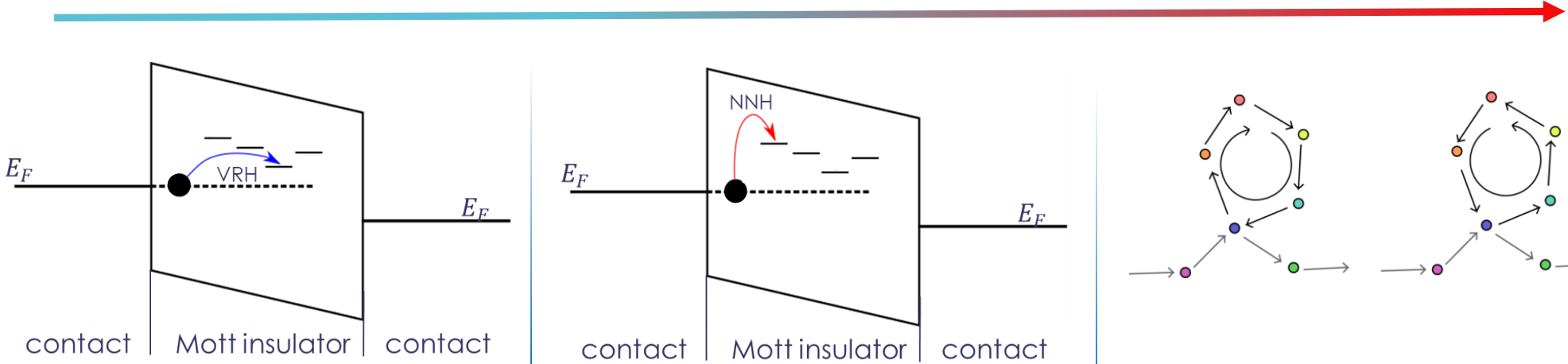
Electronic transport in disordered insulators

Expected behaviors

Haviland et al, PRL 62 18 1989



Temperature



③ Variable Range Hopping (VRH)

$$R \propto e^{\left(\frac{T_0}{T}\right)^n}$$

$$n = \frac{1}{4}, \frac{1}{3}, \frac{1}{2}$$

② Nearest Neighbor Hopping (NNH)

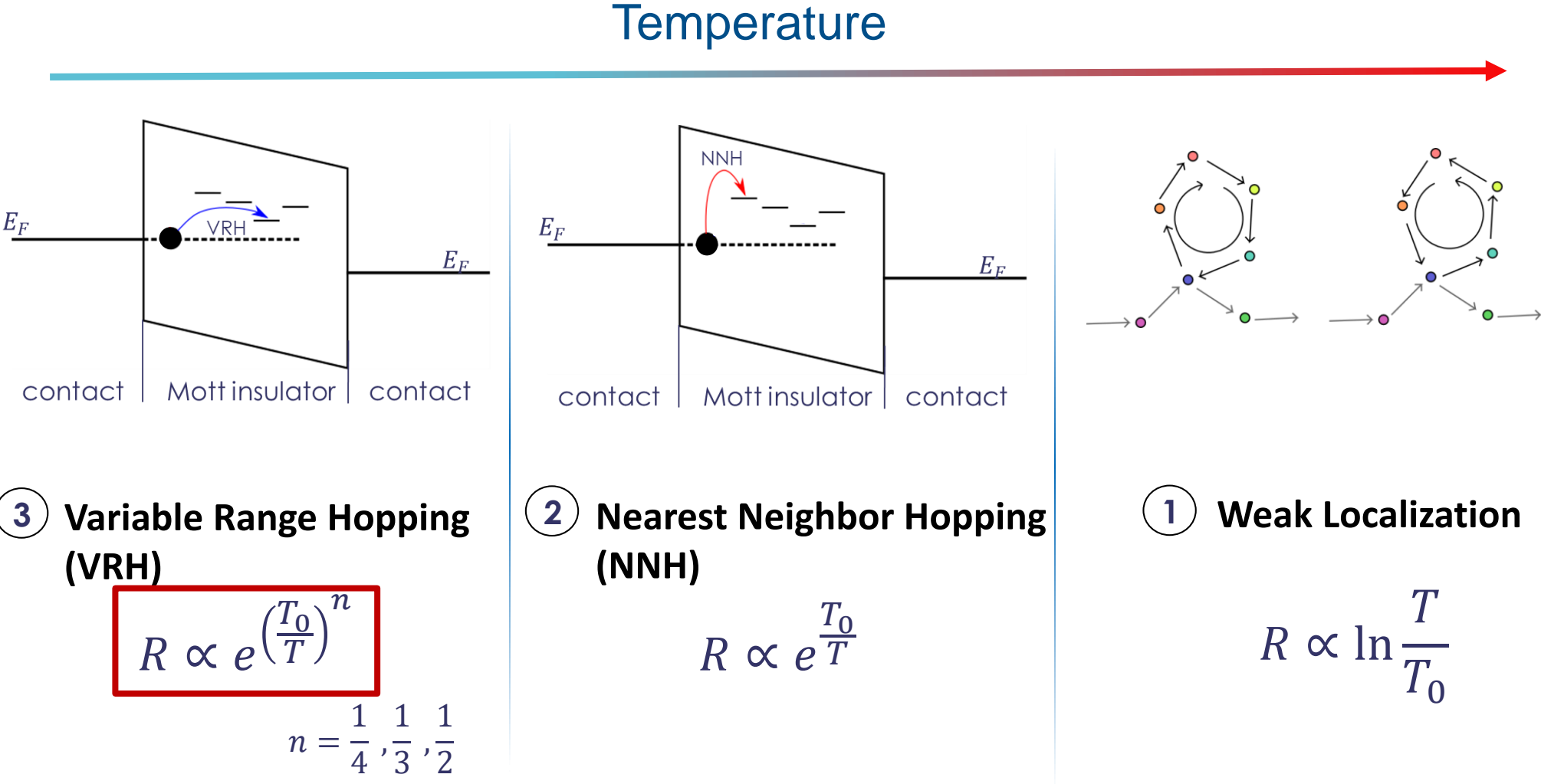
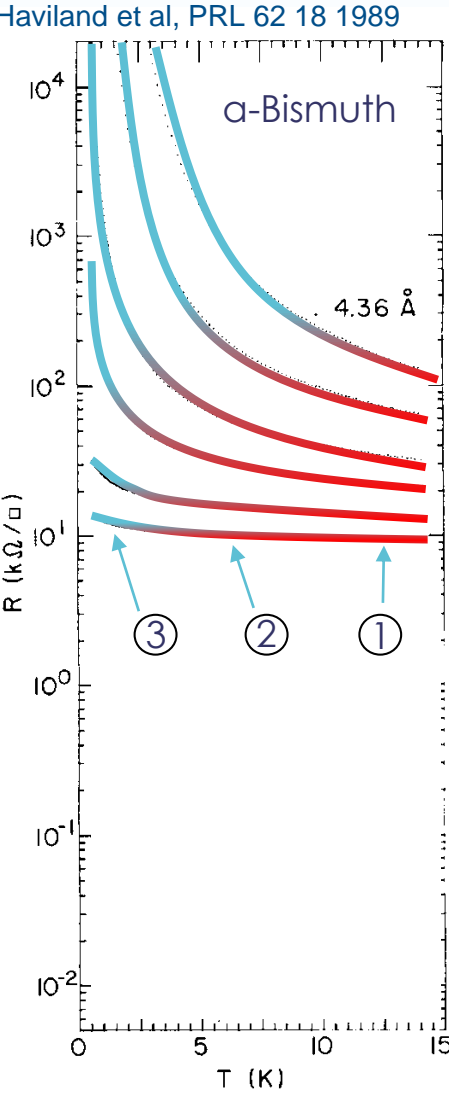
$$R \propto e^{\frac{T_0}{T}}$$

① Weak Localization

$$R \propto \ln \frac{T}{T_0}$$

Electronic transport in disordered insulators

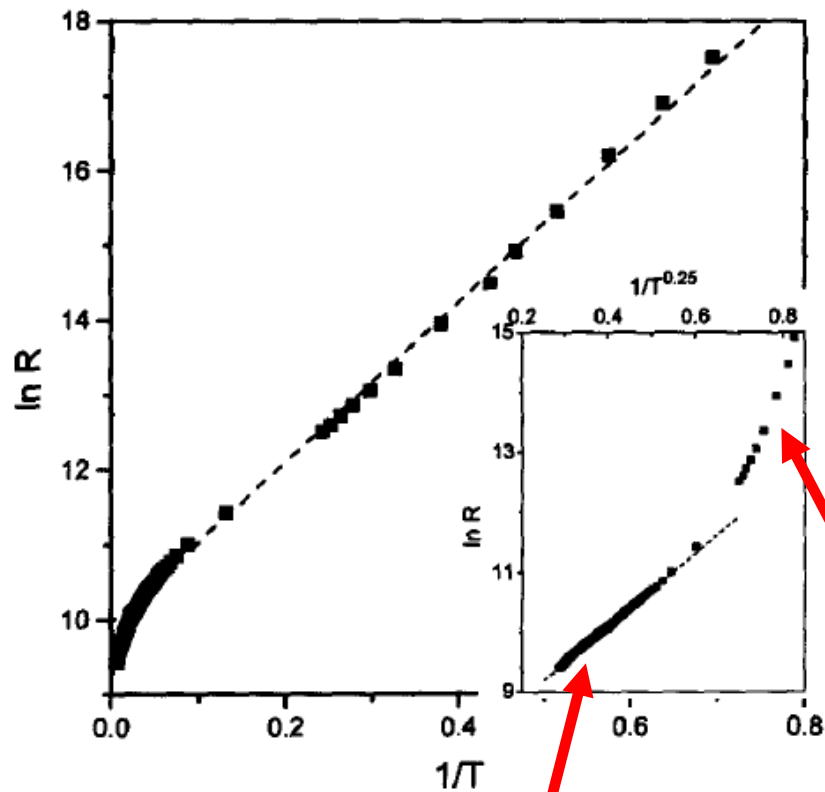
Expected behaviors



Electronic transport in disordered insulators

Unexpected behaviors

Shahar JETP Lett 88 752 2008



Mott VRH

$$R \propto e^{(T_0/T)^{1/4}}$$

Stronger than VRH

Systems with $R \propto e^{\frac{T_0}{T}}$ at the lowest temperatures

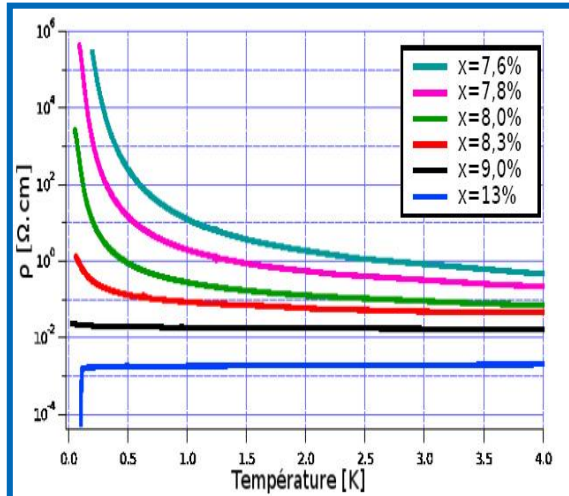
- ✓ Thin films of Al, Ga, Bi, Pb, Sn, In
Dynes *PRL* **40** 479 1978
Goldman *PRB* **40** 1 1989
Desing *PRB* **50** 3959 1994
- ✓ InOx
Gandmakher
Shahar *JETP Lett* **88** 752 2008
Kowal *Sol. St. Comm.* **90** 783 1994
- ✓ Josephson Junctions Arrays
Desing *PRB* **50** 3959 1994
- ✓ Organics
Adkins *J Phys. C* **13** 3427 1980
Tajima *EPL* **83** 27008 2008
- ✓ etc...

Nb_xSi_{1-x} thin films

Tuning the disorder

Disordered superconductor
2D ($d \ll \xi_{SC}$)

Usual disorder parameter in 2D : $R_{\square} = \frac{\rho}{d_{\perp}} \propto \frac{1}{k_F l}$

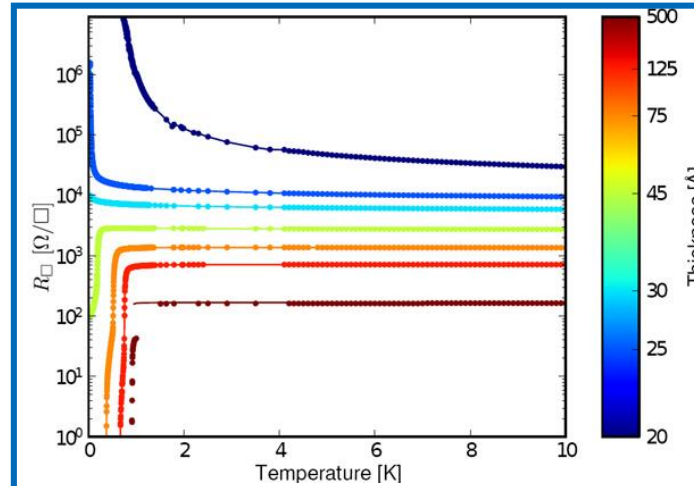


x
induced

Composition

- 3D : $d > 100$ nm

$$R_{\square} = \frac{1}{k_F l}$$

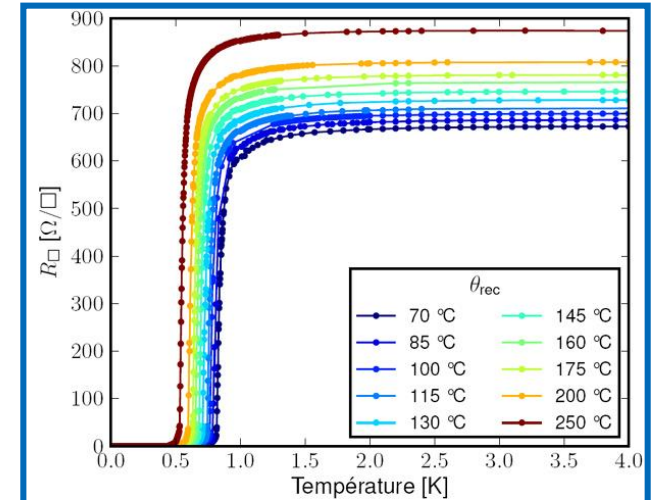


d_{\perp}
induced

Thickness

- 2D, 18%
- $\xi \sim 50$ nm

$$R_{\square} = \frac{\rho}{d}$$



θ_{anneal}
induced

Heat treatment

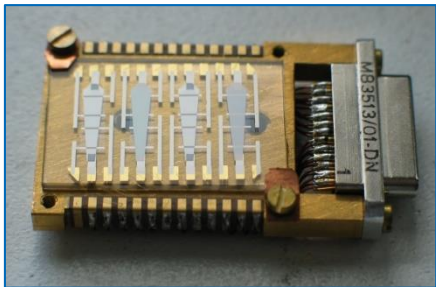
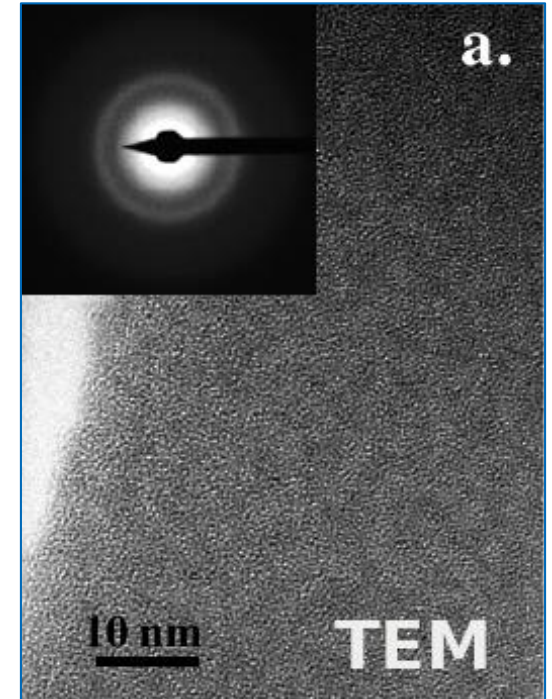
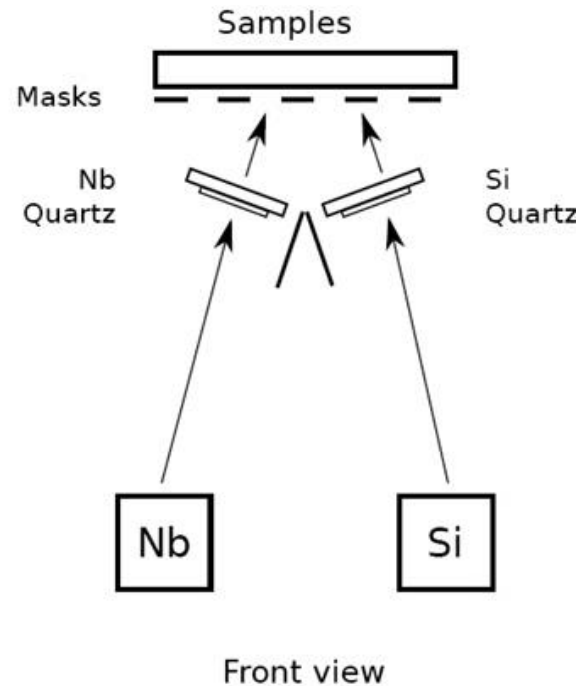
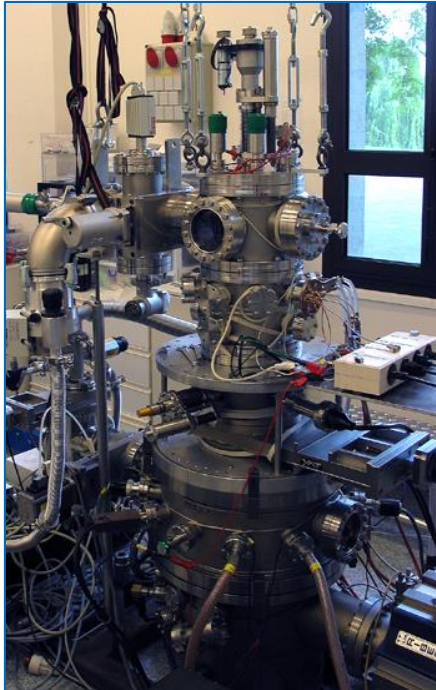
- $d=12.5$ nm, 18%

$$R_{\square} = \frac{1}{k_F l}$$

Crauste et al. *PRB* **87** 144514 2013

Nb_xSi_{1-x} thin films

Synthesis



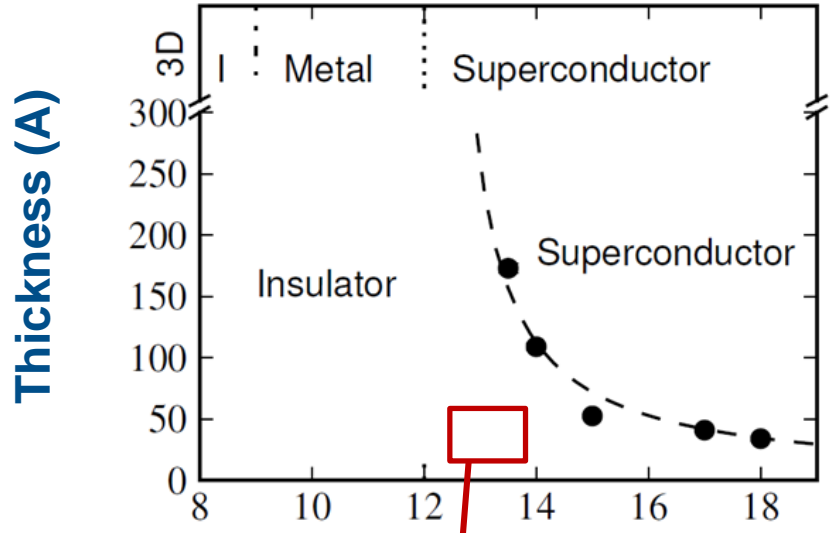
- ✓ **Morphology :**
 - ✓ Continuous down to 2.5 nm (at least)
 - ✓ Amorphous
- ✓ **Mean free path** $l = 2.6 \text{ \AA} \text{ to } 5 \text{ \AA}$

- ✓ **Electronic density** $n \sim \text{a few } 10^{27} \text{ m}^{-3}$
- ✓ **Heat treatment :**
 - ✓ No modification of n
 - ✓ No modification of the composition x

Theoretical model

Activated law at low temperature

Crauste PRB 90 060203 2014

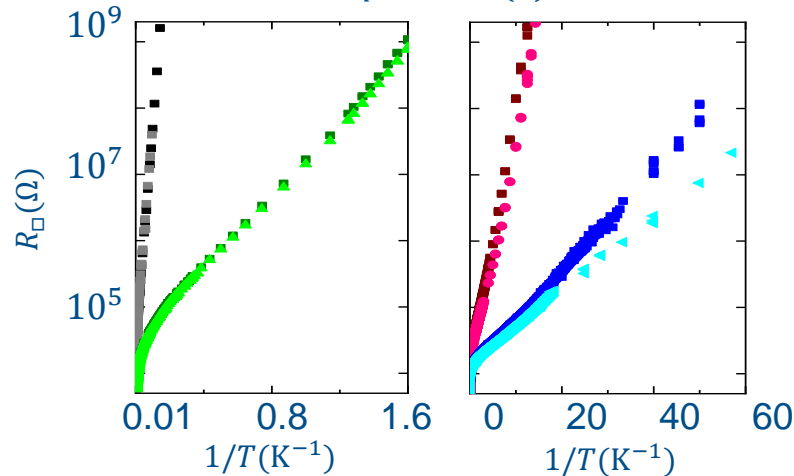
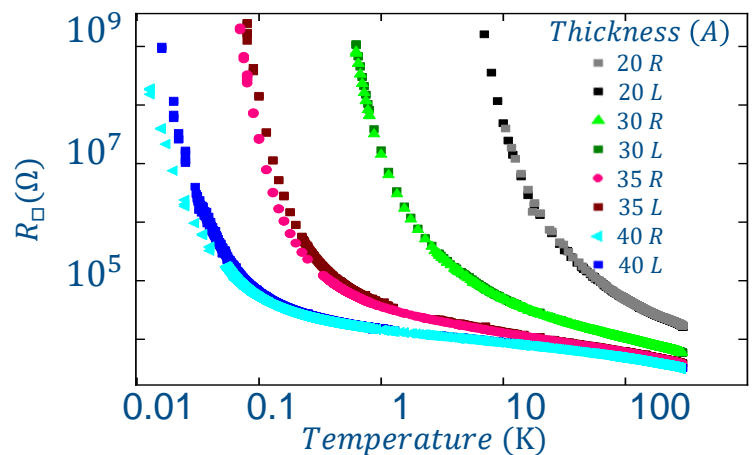


Nb Composition (%)

Films with
 $d = [20, 50 \text{ A}]$
 $x = 13.5 \%$

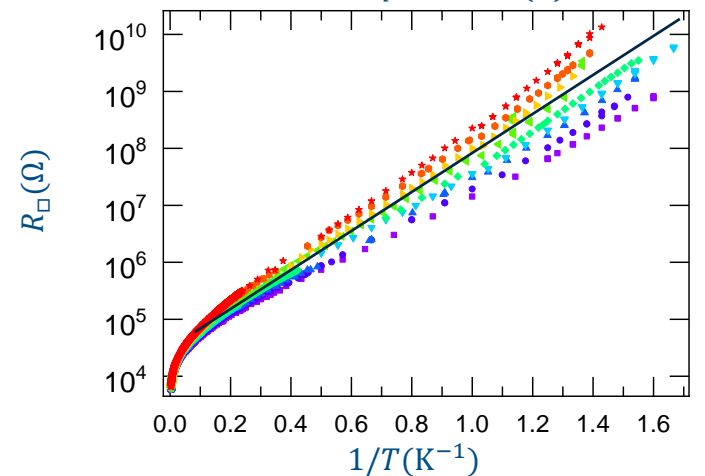
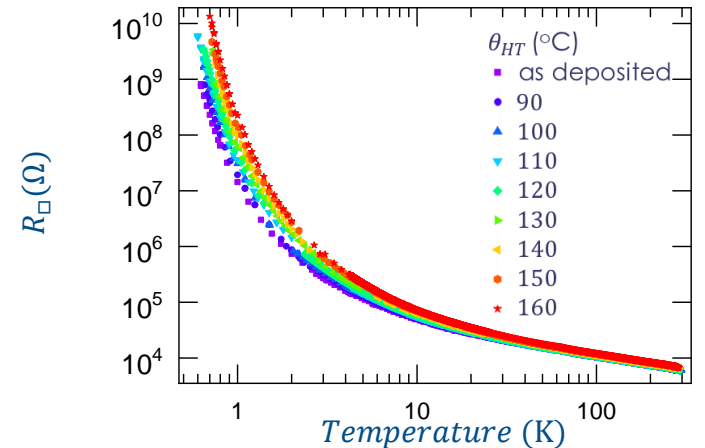
Thickness

As deposited, $x = 13.5\%$



Heat treatment

30 A, $x = 13.5\%$

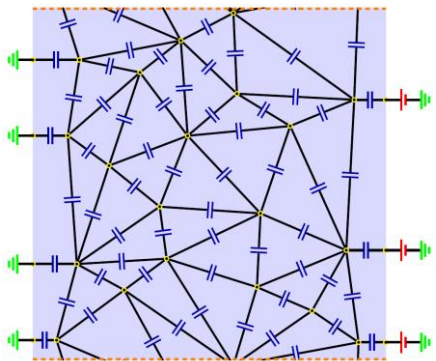
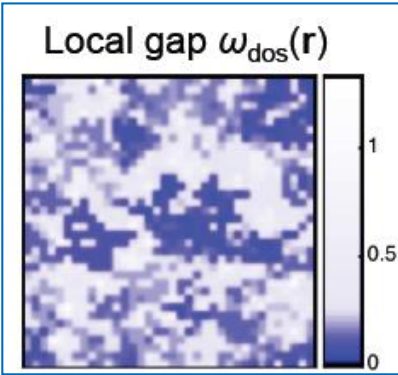


Theoretical model

Activated law at low temperature

Mechanisms for $R \propto e^{\frac{T_0}{T}}$ at low T

Charging energies (inhomogeneous systems)



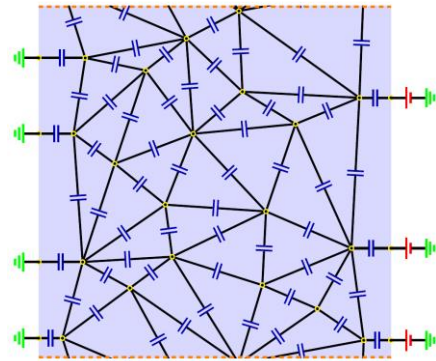
Bouadim et al., Nat. Phys., 7 884 2011

Divergent localization length ξ_{loc} close the transition

- Divergent κ → logarithmic Coulomb interactions
- charging energy

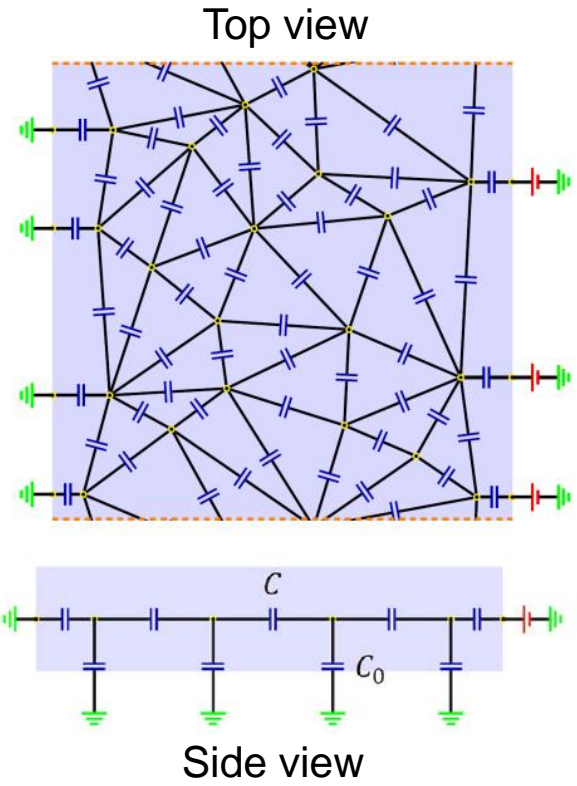
$$V(r) \sim \frac{e^2}{2\pi\epsilon_0\kappa d} \ln \frac{\kappa d}{r}$$

$$\text{With } \kappa = \kappa_0 + 4\pi\beta_2 \frac{e^2}{a} N(E_F)\xi_{loc}^2$$

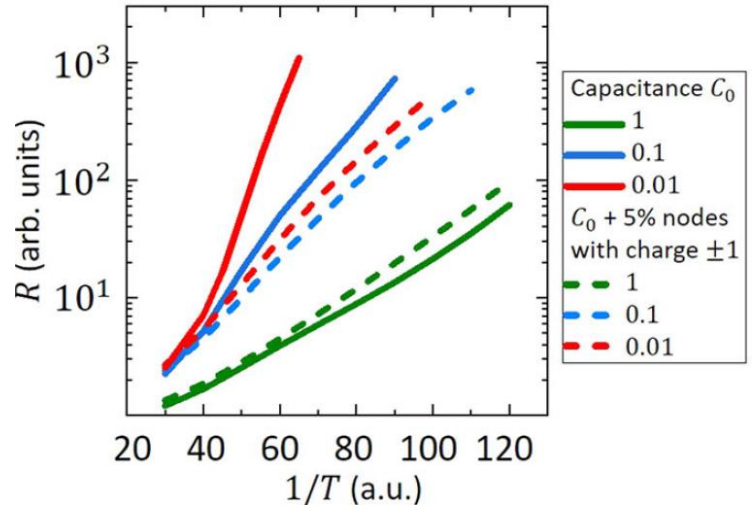


Theoretical model

Activated law at low temperature

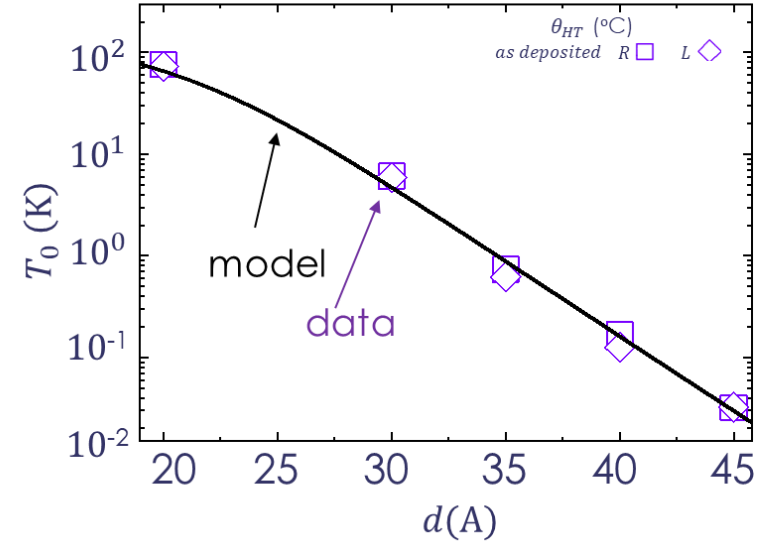


- Random distribution of capacitances
- ✓ Fixed boundary conditions
 - ✓ Fluctuating charges



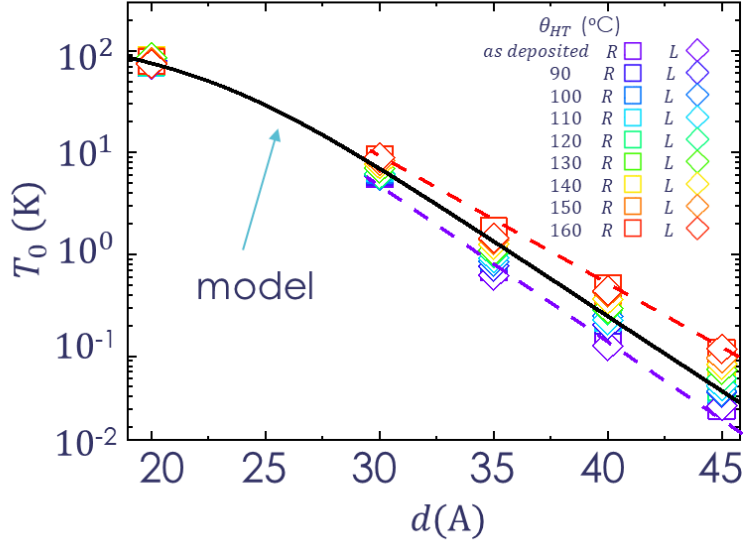
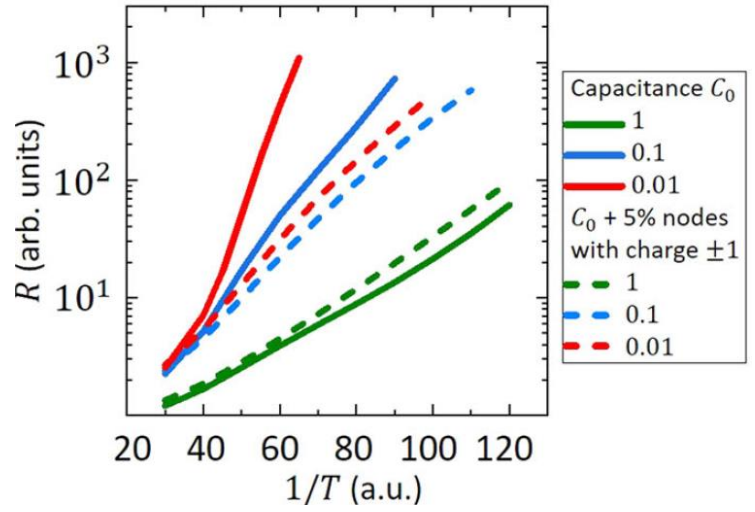
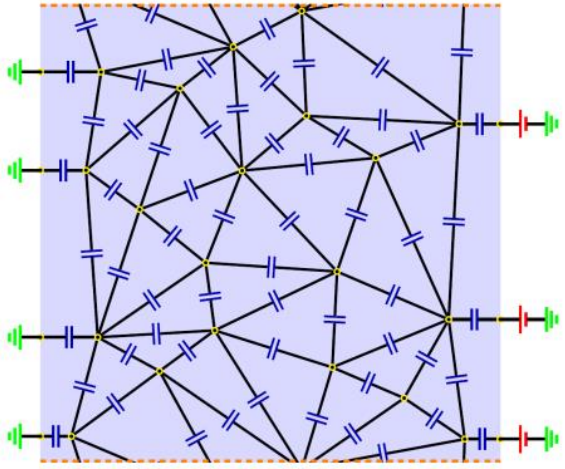
$$R \propto e^{\frac{T_0}{T}}$$

$$k_B T_0 \sim \frac{e^2}{4 \pi \epsilon_0 \kappa d} \ln \left(\frac{\kappa d}{a} \right)$$



Theoretical model

Activated law at low temperature



- Random distribution of capacitances
- ✓ Fixed boundary conditions
 - ✓ Fluctuating charges

$$R \propto e^{\frac{T_0}{T}}$$

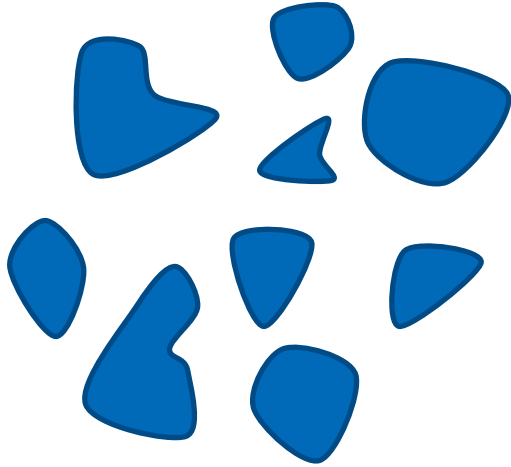
$$k_B T_0 \sim \frac{e^2}{4 \pi \epsilon_0 \kappa d} \ln \left(\frac{\kappa d}{a} \right)$$

$$\kappa = \kappa_0 + 4 \pi \beta_2 \frac{e^2}{a} N(E_F) \xi_{loc}^2$$

θ_{HT} modifies microscopic disorder
 → Modifies κ

Theoretical model

Activated law at low temperature



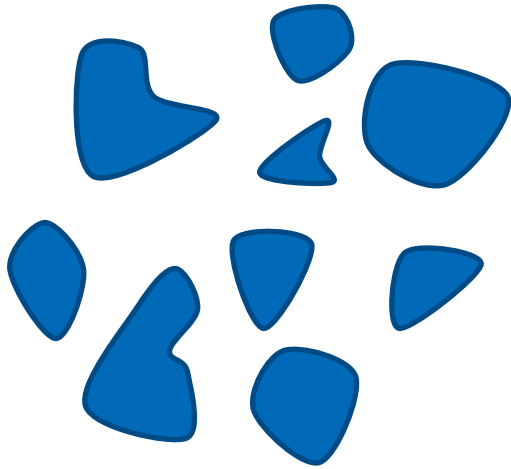
- ✓ Electronic granularity due to:
 - ✓ Inhomogeneities
 - ✓ High dielectric constant κ

$$k_B T_0 \sim \frac{e^2}{4 \pi \epsilon_0 \kappa d} \ln \left(\frac{\kappa d}{a} \right)$$

$$\text{with } \kappa = \kappa_0 + 4 \pi \beta_2 \frac{e^2}{a} N(E_F) \xi_{loc}^2$$

Theoretical model

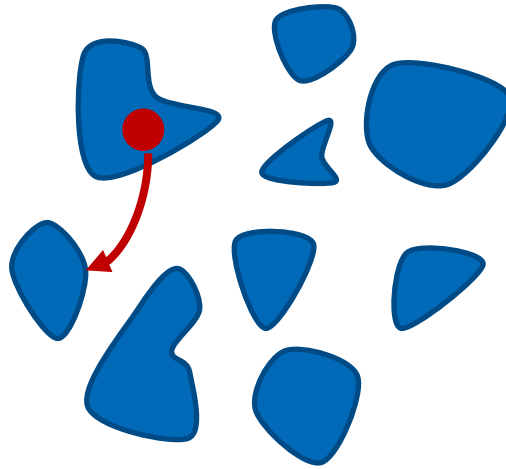
Activated law at low temperature



- ✓ Electronic granularity due to:
 - ✓ Inhomogeneities
 - ✓ High dielectric constant κ

$$k_B T_0 \sim \frac{e^2}{4 \pi \epsilon_0 \kappa d} \ln \left(\frac{\kappa d}{a} \right)$$

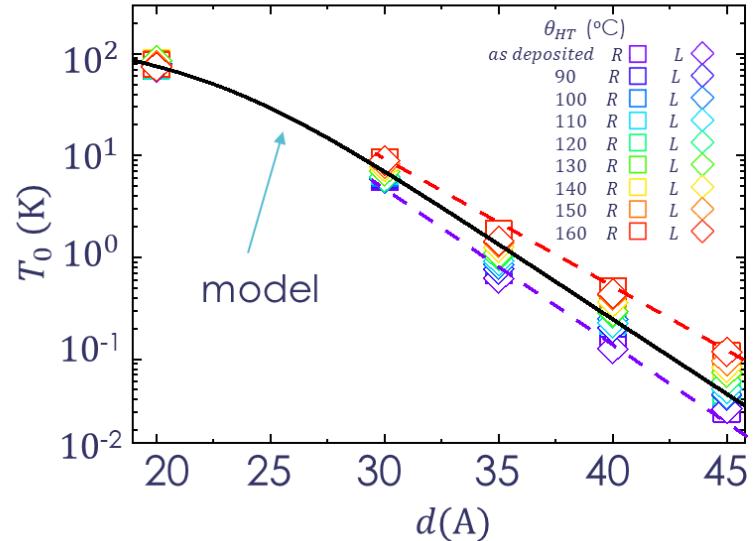
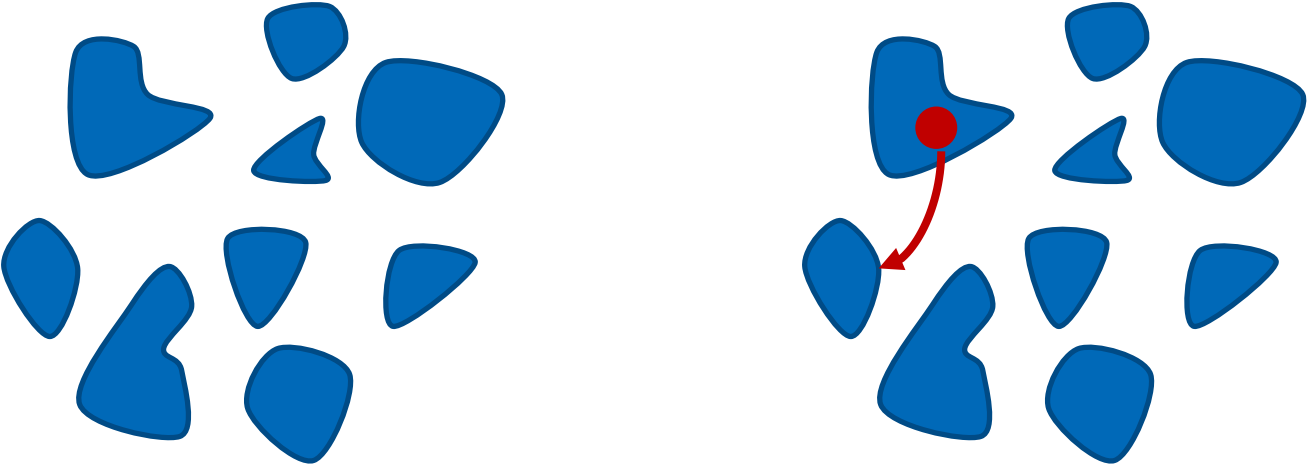
$$\text{with } \kappa = \kappa_0 + 4 \pi \beta_2 \frac{e^2}{a} N(E_F) \xi_{loc}^2$$



- ✓ Electrons hopping between grains

Theoretical model

Activated law at low temperature



✓ Electronic granularity due to:

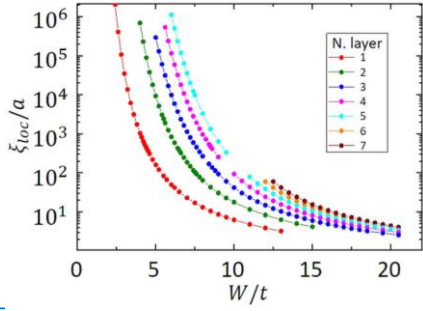
- ✓ Inhomogeneities
- ✓ High dielectric constant κ

$$k_B T_0 \sim \frac{e^2}{4 \pi \epsilon_0 \kappa d} \ln \left(\frac{\kappa d}{a} \right)$$

with $\kappa = \kappa_0 + 4 \pi \beta_2 \frac{e^2}{a} N(E_F) \xi_{loc}^2$

✓ Electrons hopping between grains

W = disorder level
 t = kinetic energy



✓ Experimentally: $T_0 \propto e^{-\zeta d}$

✓ Theoretically: $T_0 \propto \frac{1}{\kappa d} \simeq \frac{1}{\xi_{loc}^2 d}$

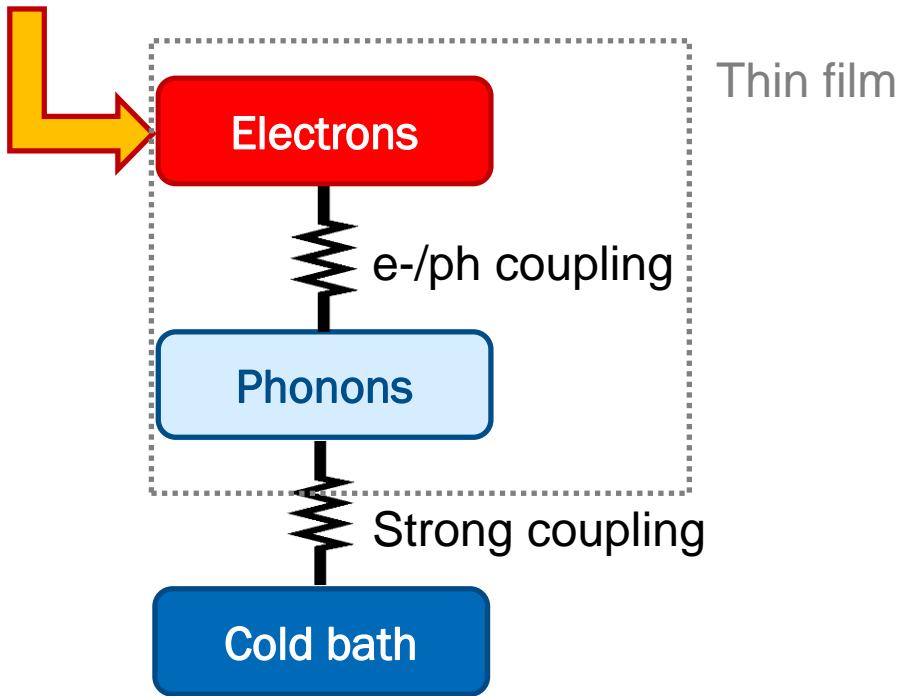
✓ This implies:

$$\xi_{loc} \simeq A e^{\frac{\eta d}{W^2}}$$

ELECTRON-PHONON DECOUPLING IN THE INSULATOR

E-Phonon coupling

Electrical measurement



✓ Heat balance equation

$$P = VI = g_{e-ph} (T_e^\beta - T_{ph}^\beta)$$

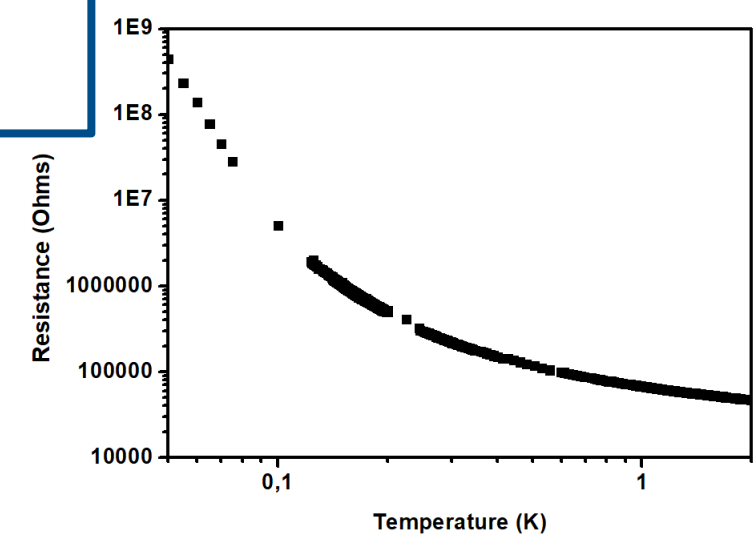
Expression valid for metals

- Assumes all power go to phonons

Determined by R(T) curve:

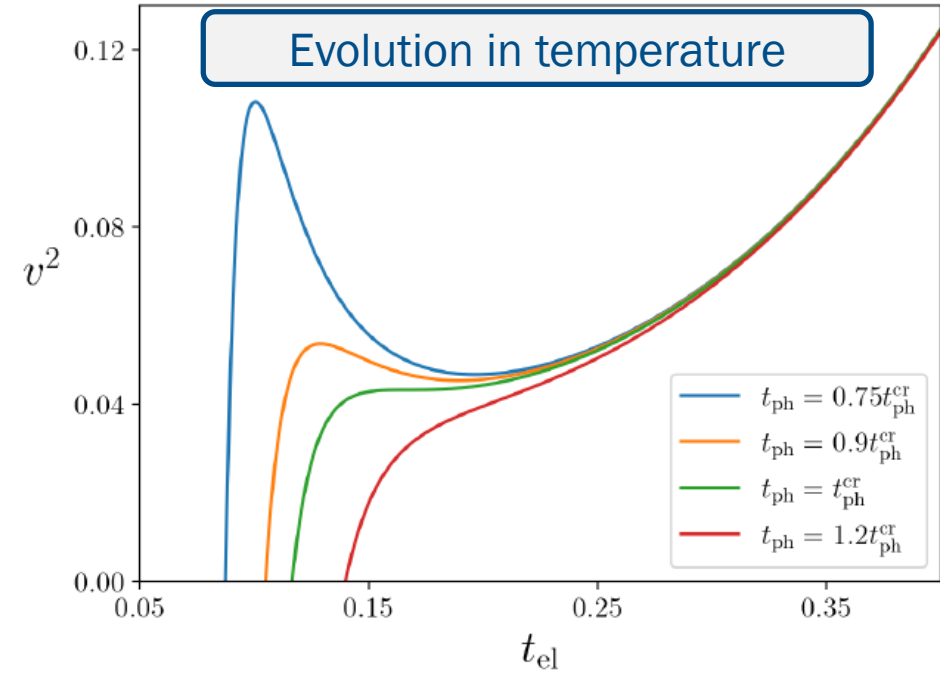
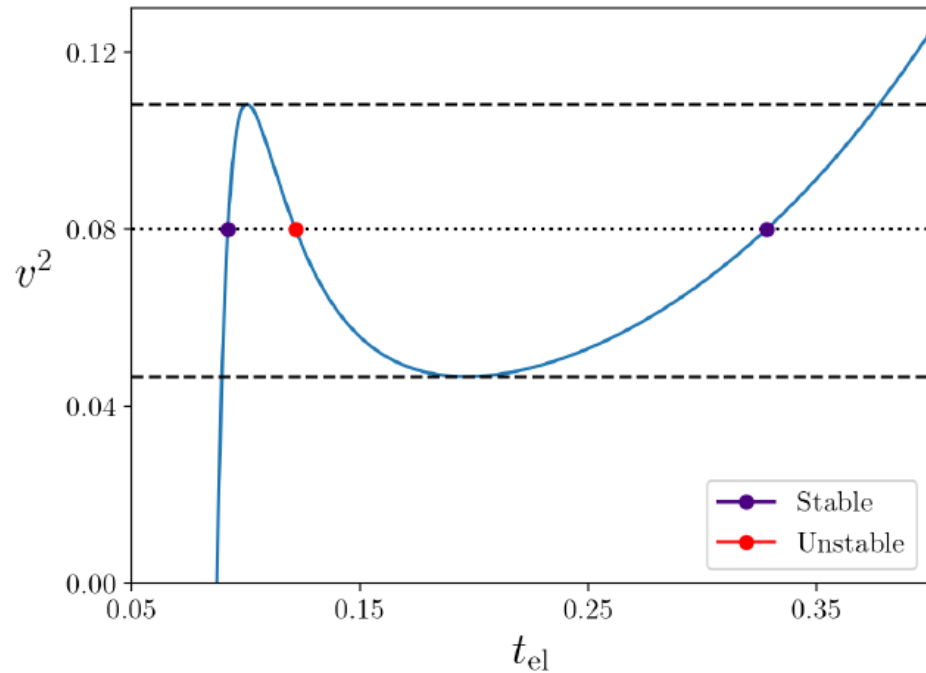
- Assumes resistance is only fct of T_e .

Exact value not really known



E-Phonon coupling

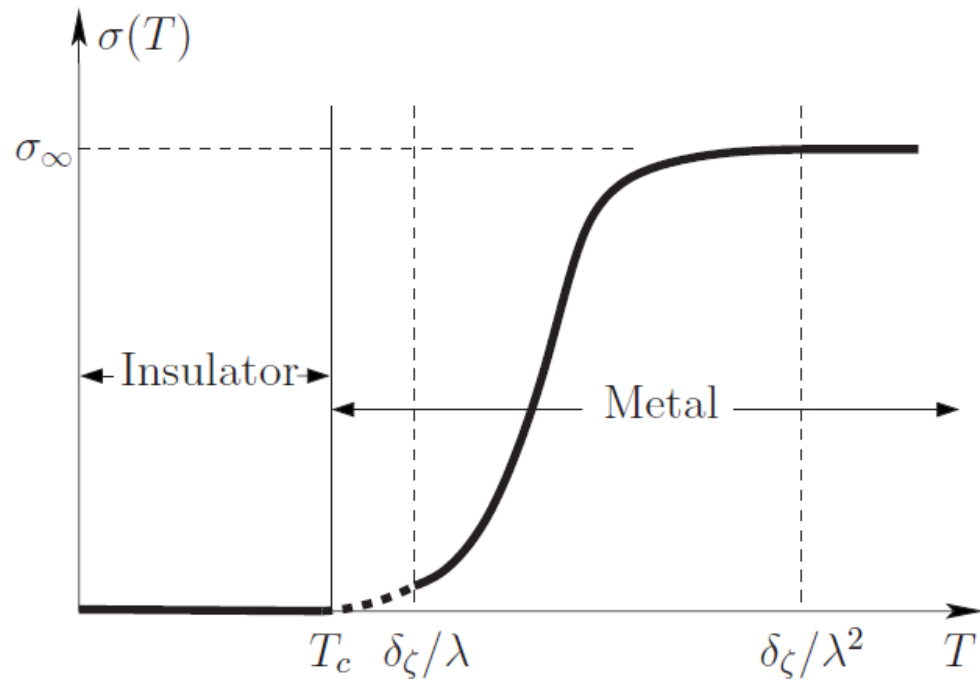
McArdle and Lerner Scientific Reports 11 24293 2021



$$P = \frac{V^2}{R} = g_{e-ph} \left(T_e^\beta - T_{ph}^\beta \right)$$

- ✓ At low enough T, there is *always* a bistability
- ✓ The max T at which bistability observed does not evolve with g_{e-ph} (assuming constant $R(T)$).

E-Phonon coupling



- ✓ Disordered superconductors as a possible platform for MBL
- ✓ Weak e-/phonon coupling
- ✓ Zero conductivity below T_c

Basko, Aleiner, Altshuler PRB 76, 052203 2007

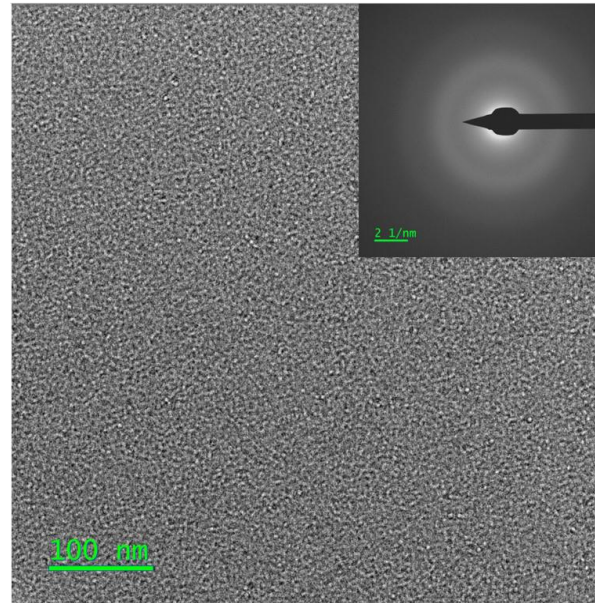
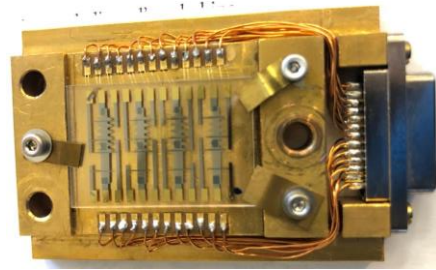
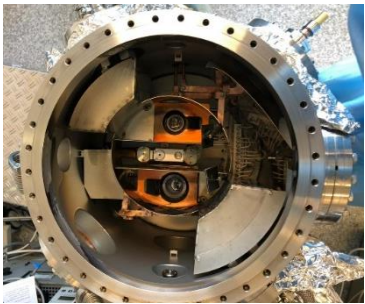
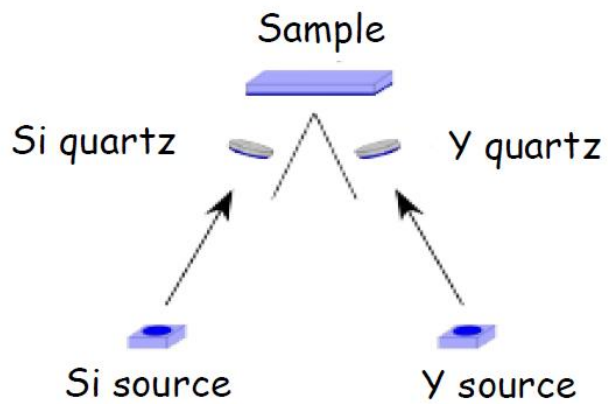
Altshuler, Kravtsov, Lerner, Aleiner PRL 102, 176803 2009

Y_xSi_{1-x} thin films

Synthesis

E-beam co-deposition

TEM



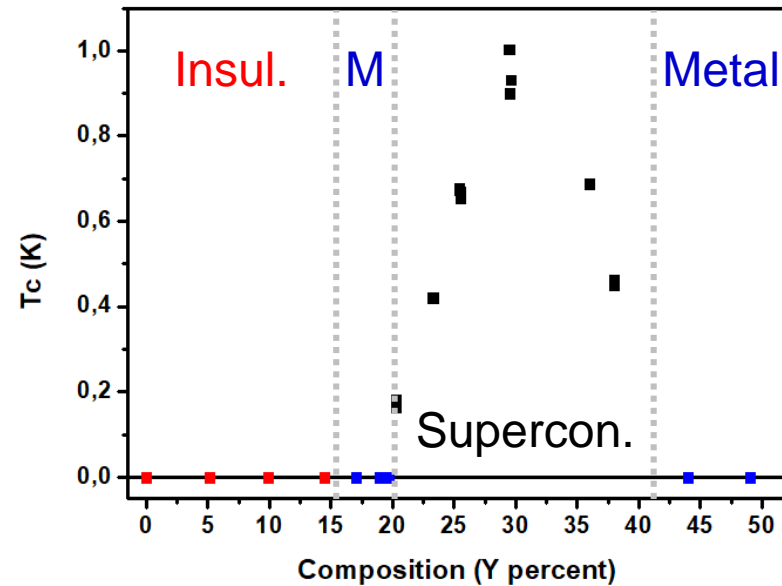
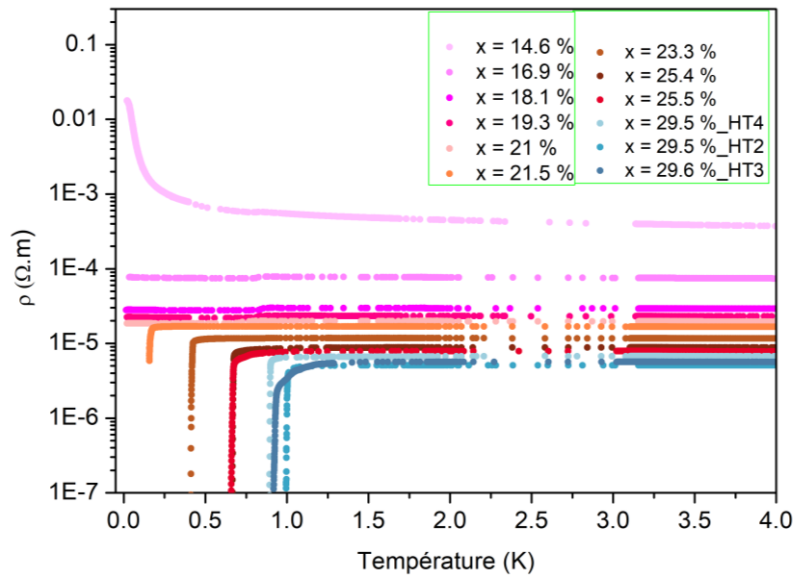
- ✓ Amorphous
- ✓ Mean free path $l \sim 2 - 5 \text{ \AA}$
- ✓ Electronic density $n \sim \text{a few } 10^{27} \text{ m}^{-3}$
- ✓ Heat treatment until 500°C :
 - ✓ No modification of the composition x

Y_xSi_{1-x} thin films

Phase diagram

Composition

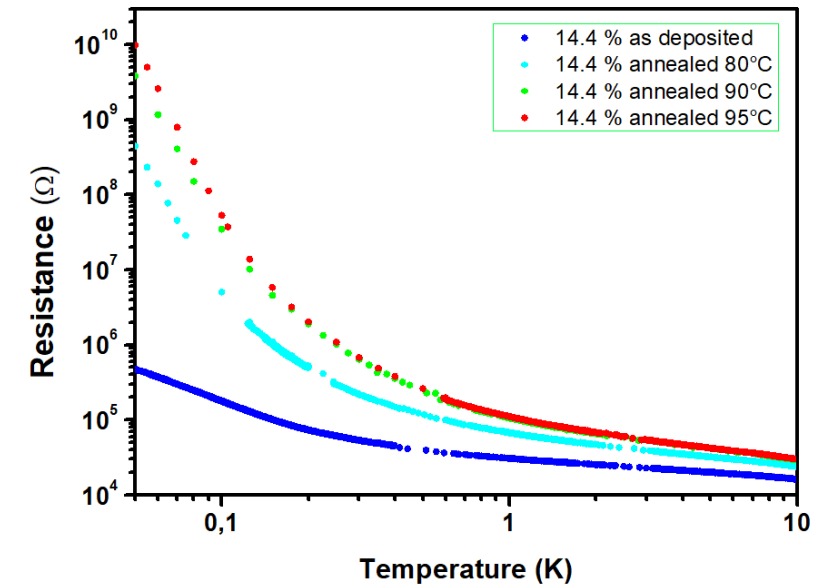
As deposited, $d \in [30,60]$ nm



- ✓ Metal-to-Insulator transition: $x \sim 16\%$
- ✓ Superconducting for $20\% < x < 40\%$

Heat treatment

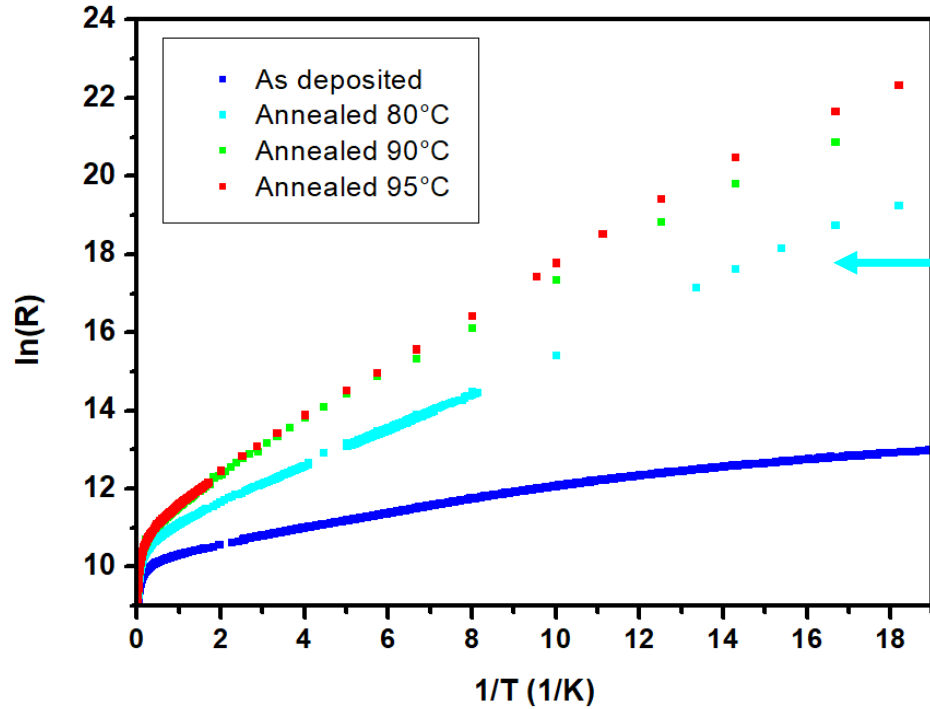
14,4%, $d = 30$ nm



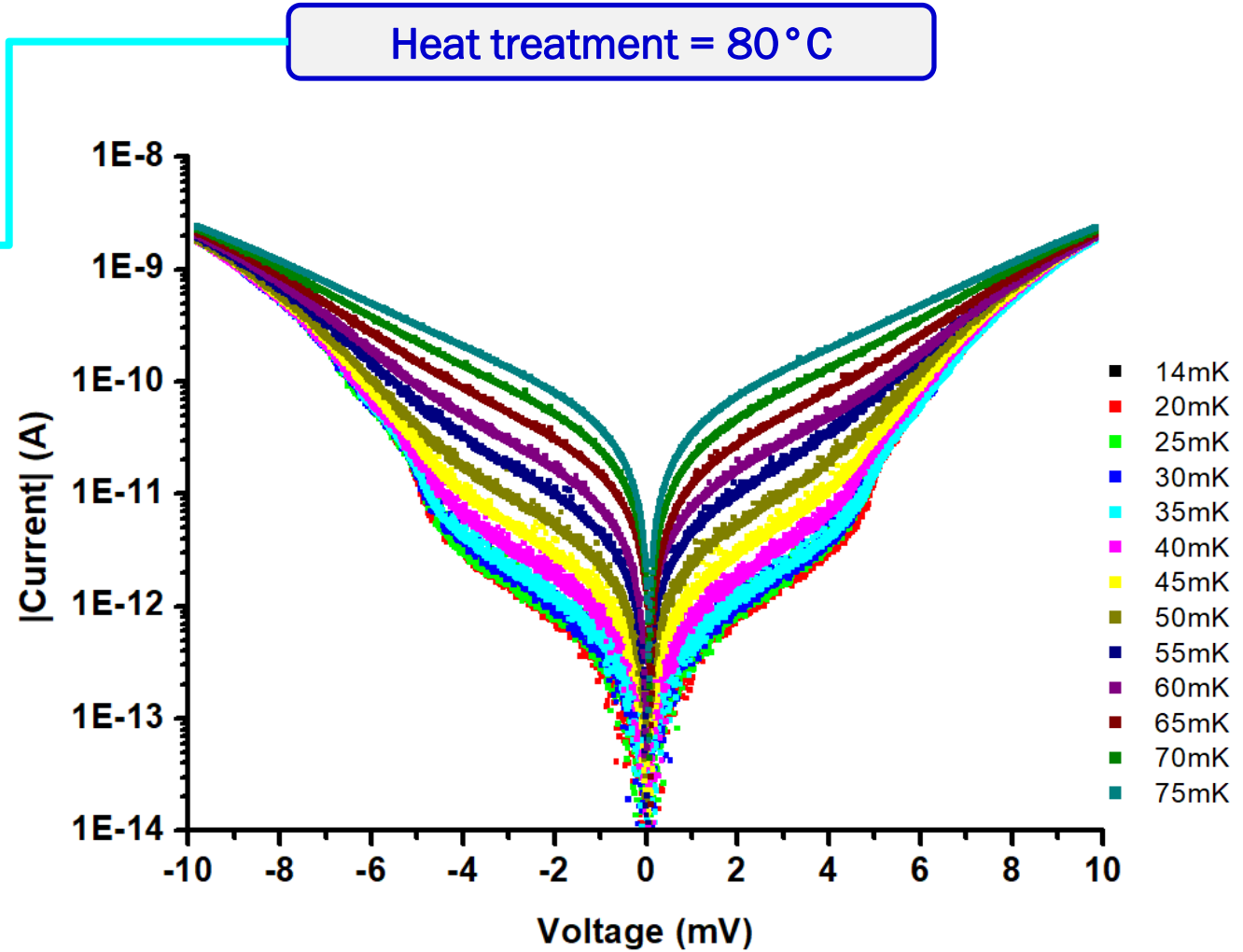
- ✓ Heat treatment renders film more insulating

I(V) curves

Low disorder

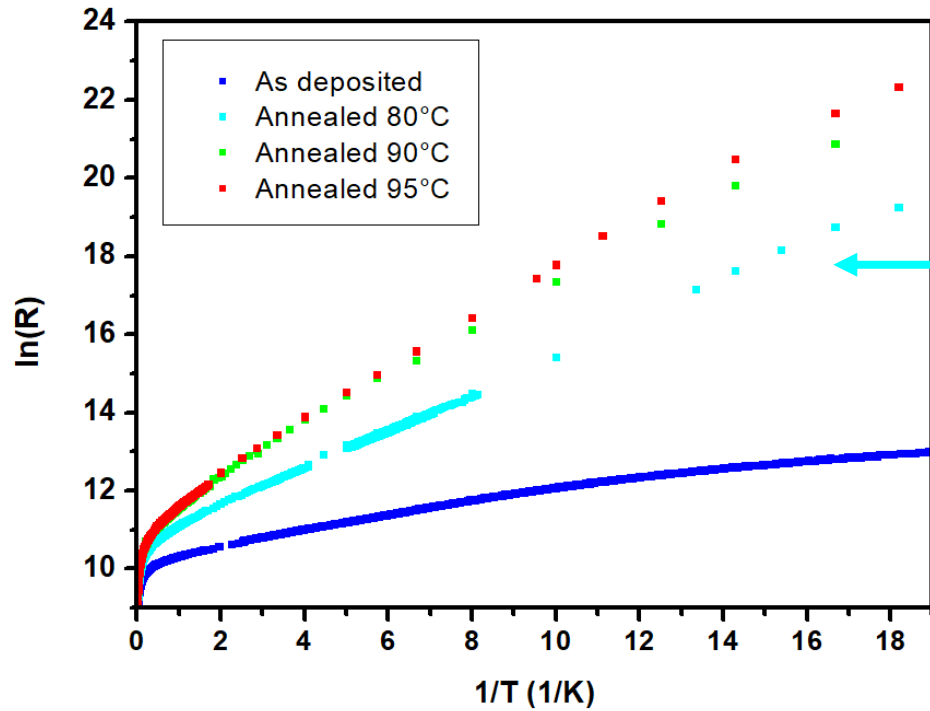


✓ Activated behavior at low temperature

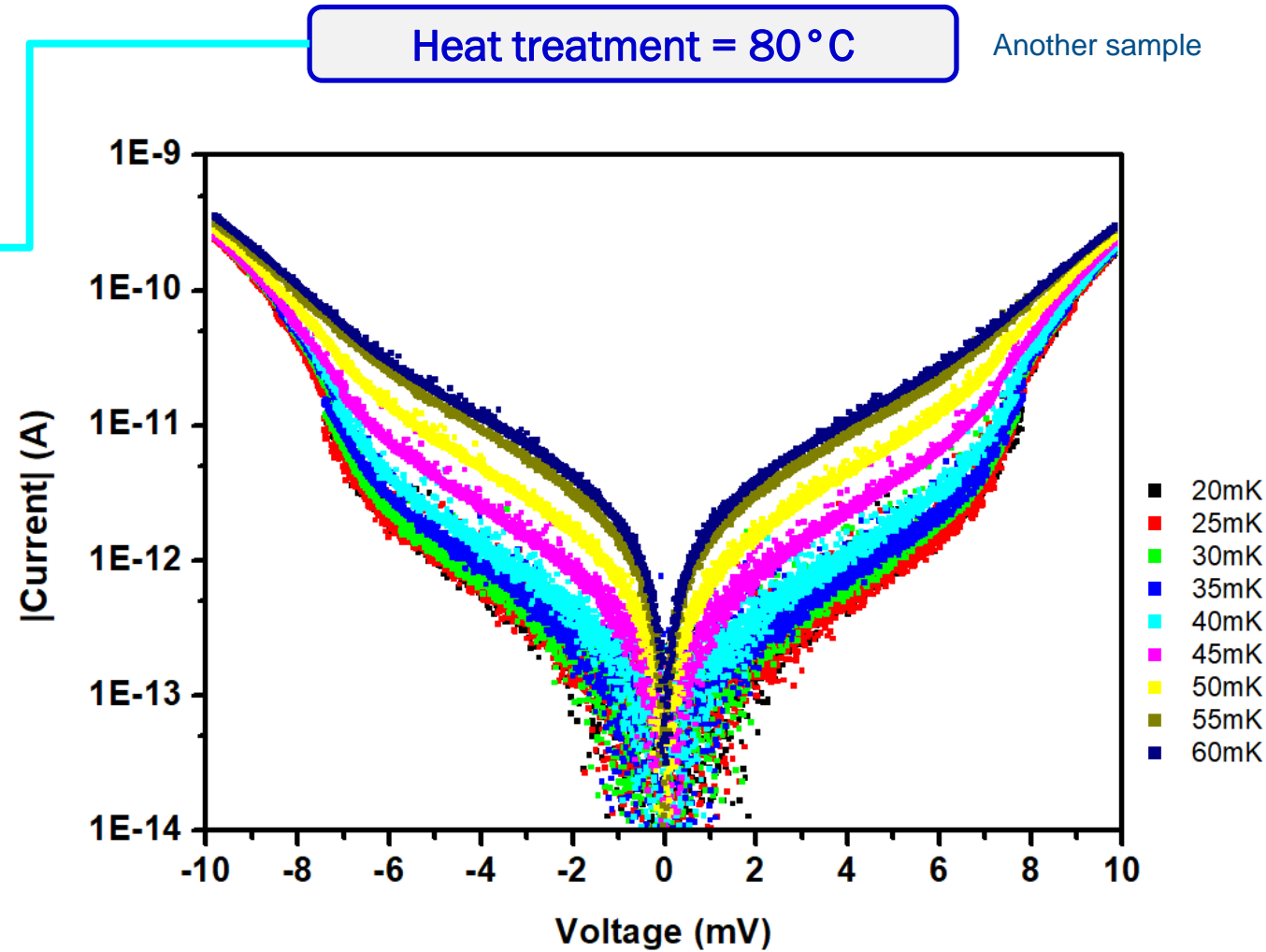


I(V) curves

Low disorder

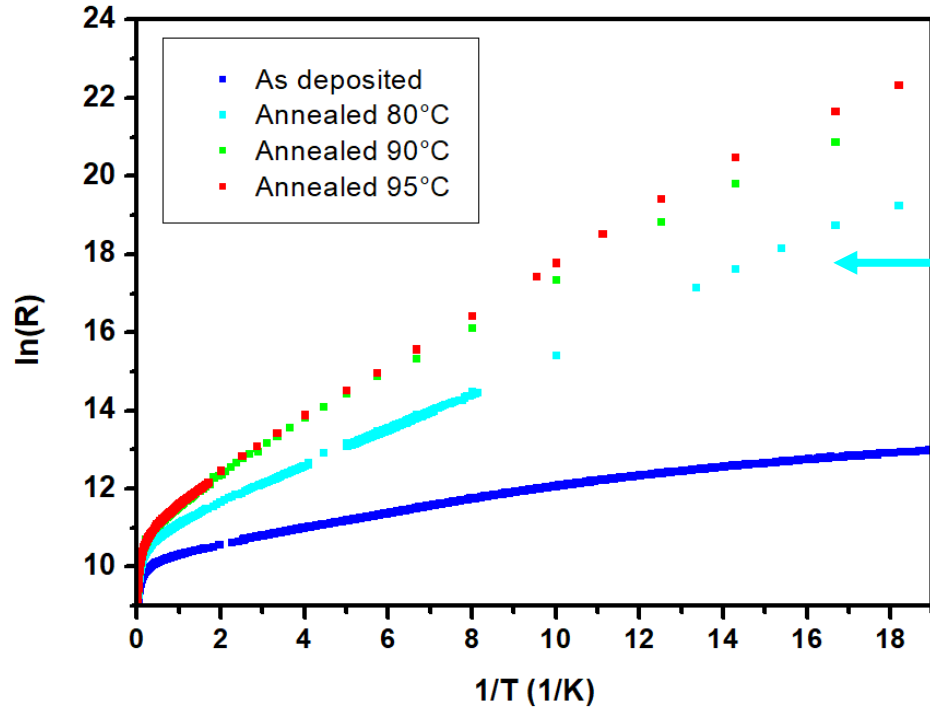


✓ Activated behavior at low temperature

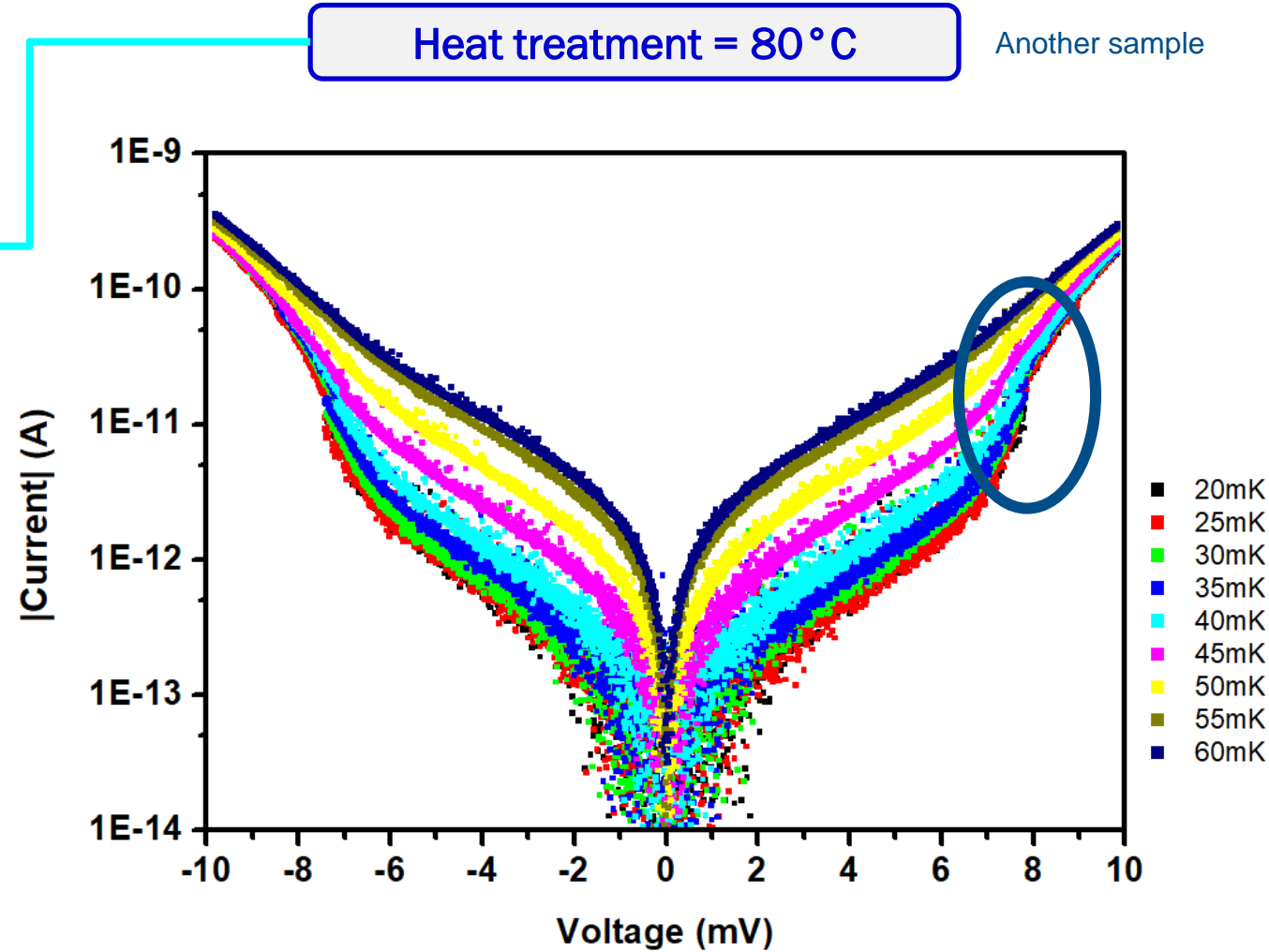


I(V) curves

Low disorder

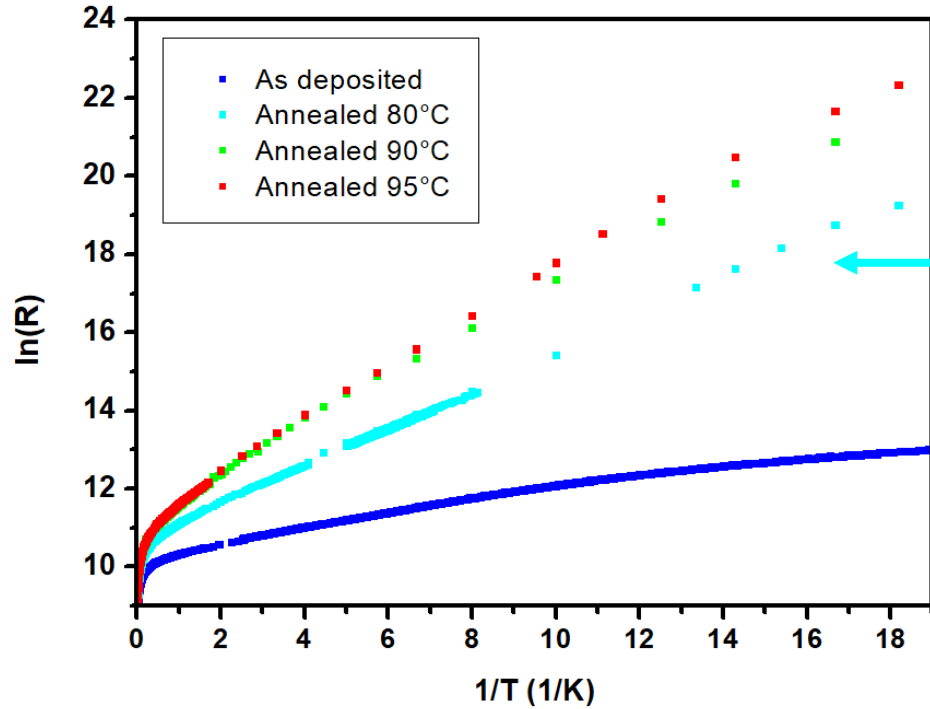


✓ Activated behavior at low temperature

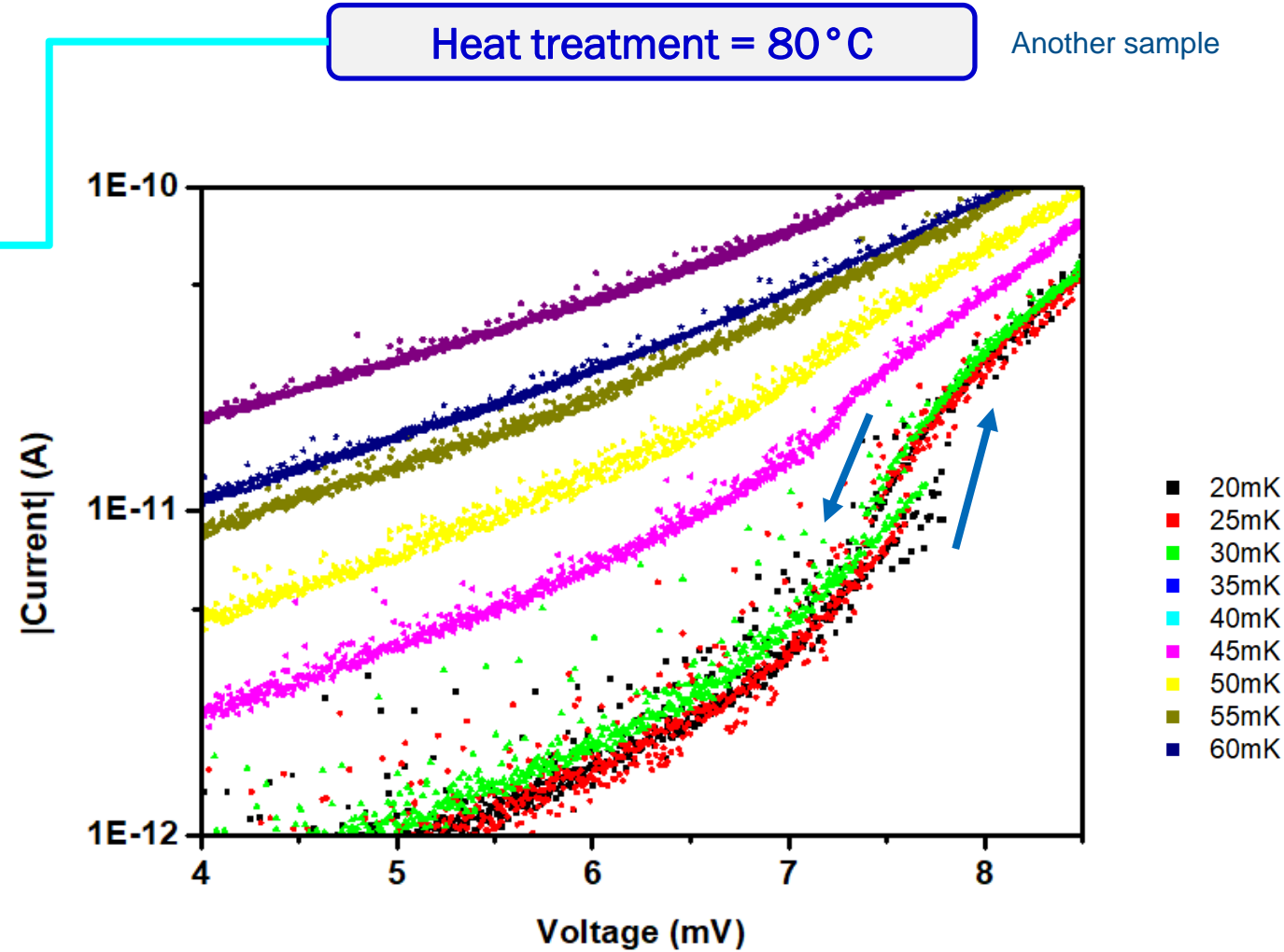


I(V) curves

Low disorder

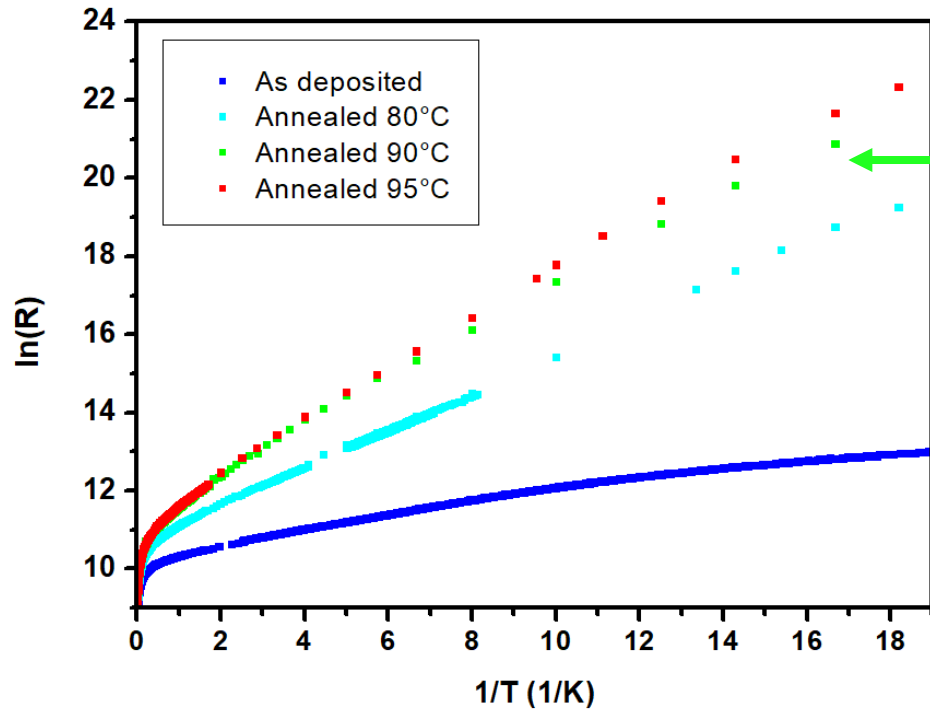


✓ Activated behavior at low temperature

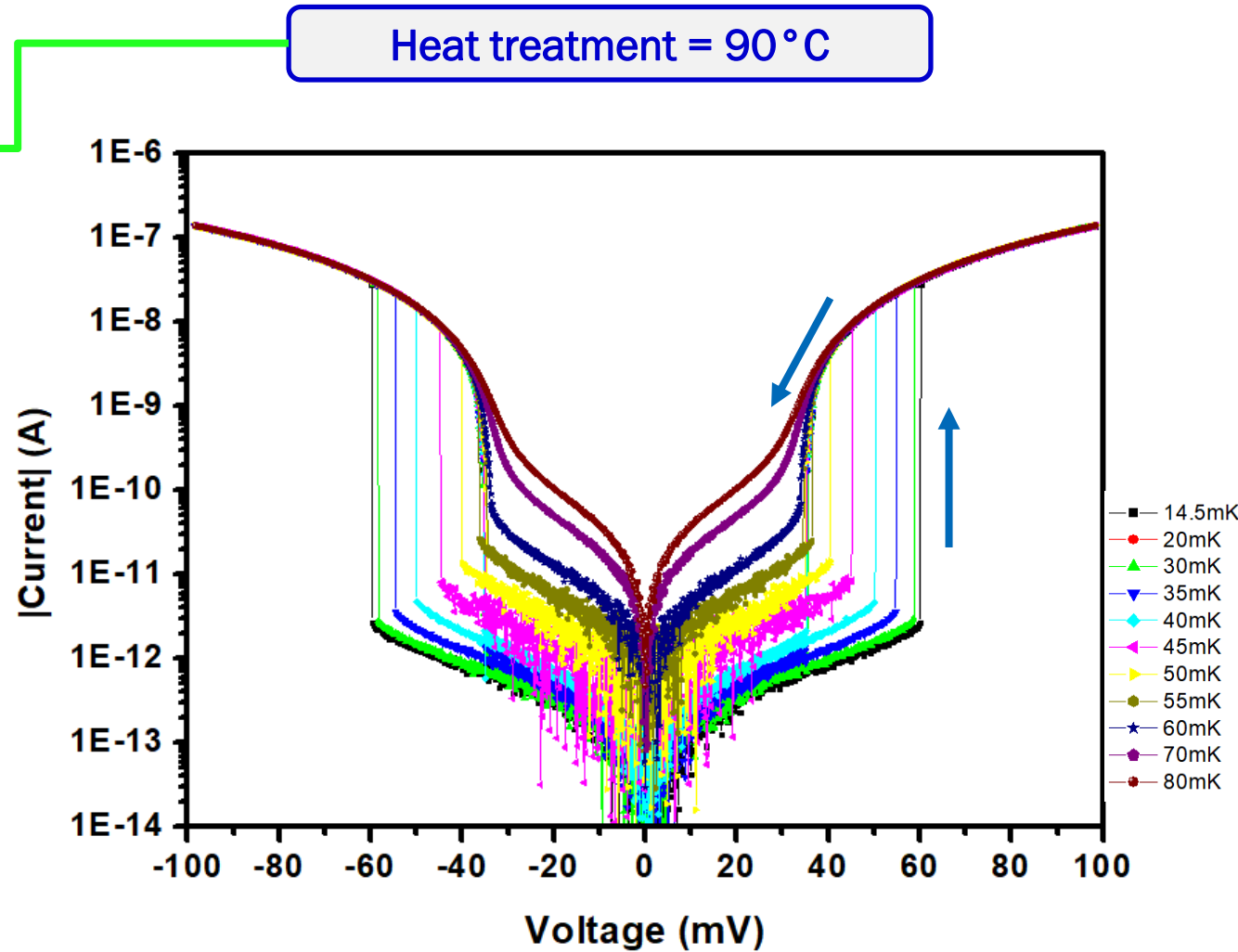


I(V) curves

Higher disorder

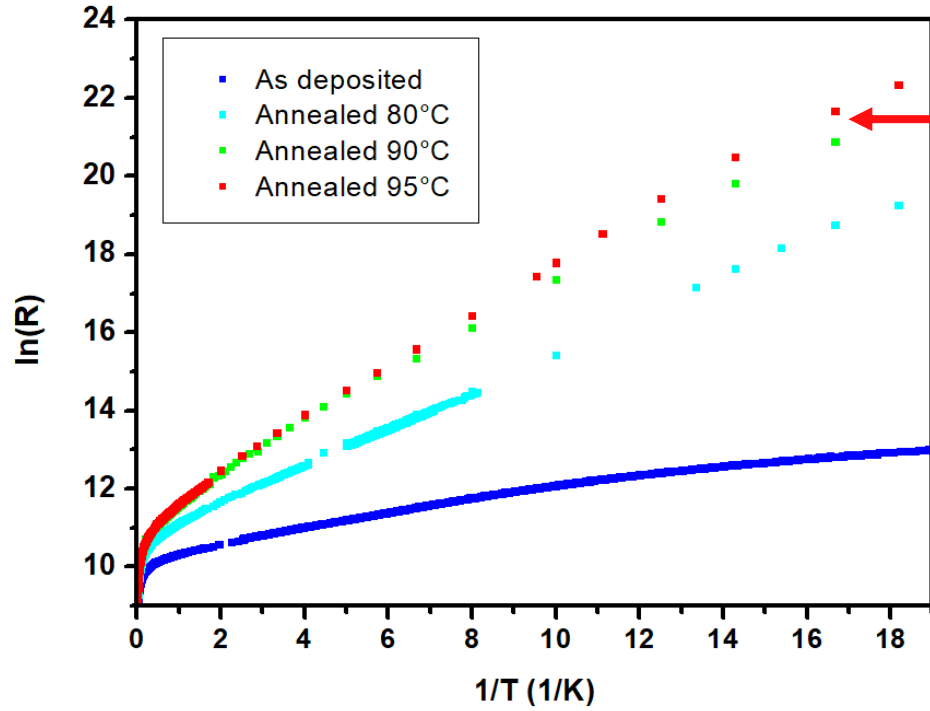


✓ Activated behavior at low temperature



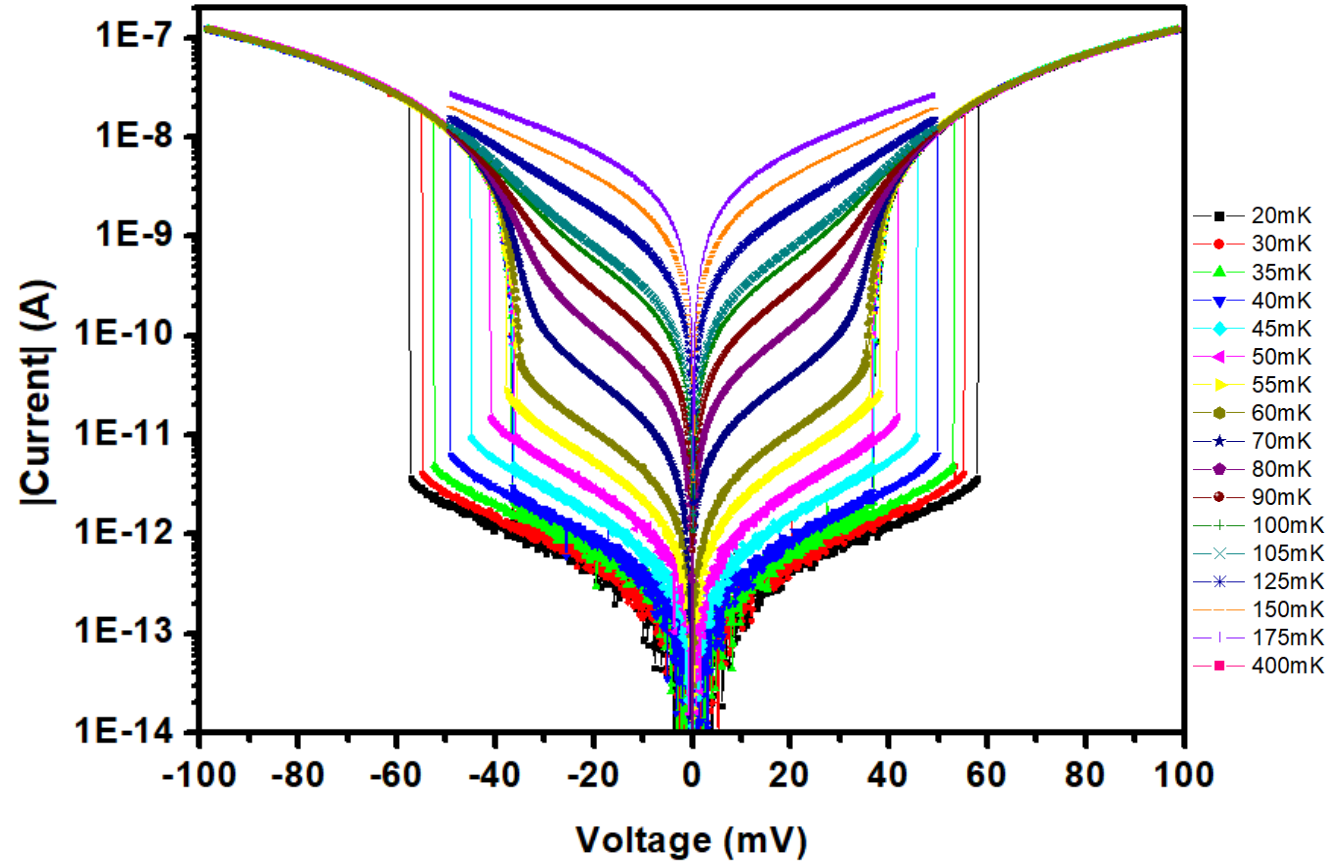
I(V) curves

Even larger disorder



✓ Activated behavior at low temperature

Heat treatment = 95°C



I(V) curves

Comparison with heat balance equation

✓ **Heat balance equation**

$$P = g_{e-ph} \left(T_e^\beta - T_{ph}^\beta \right)$$

✓ **Activated transport**

$$R = R_0 e^{T_0/T_e}$$

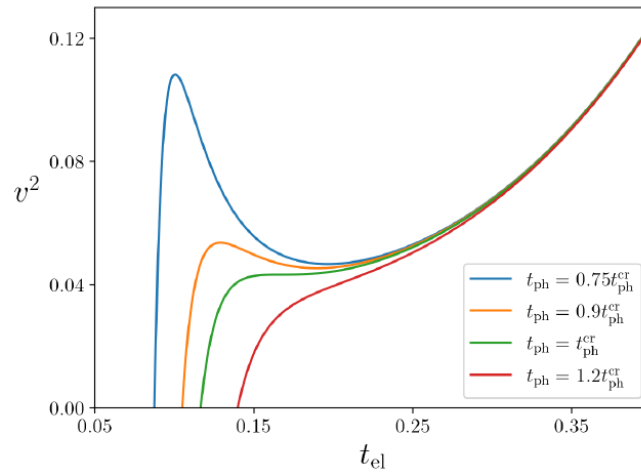
✓ **Maximum T_{ph} for bistability**

$$T_c = (\beta + 1)^{\frac{\beta+1}{\beta}} T_0$$

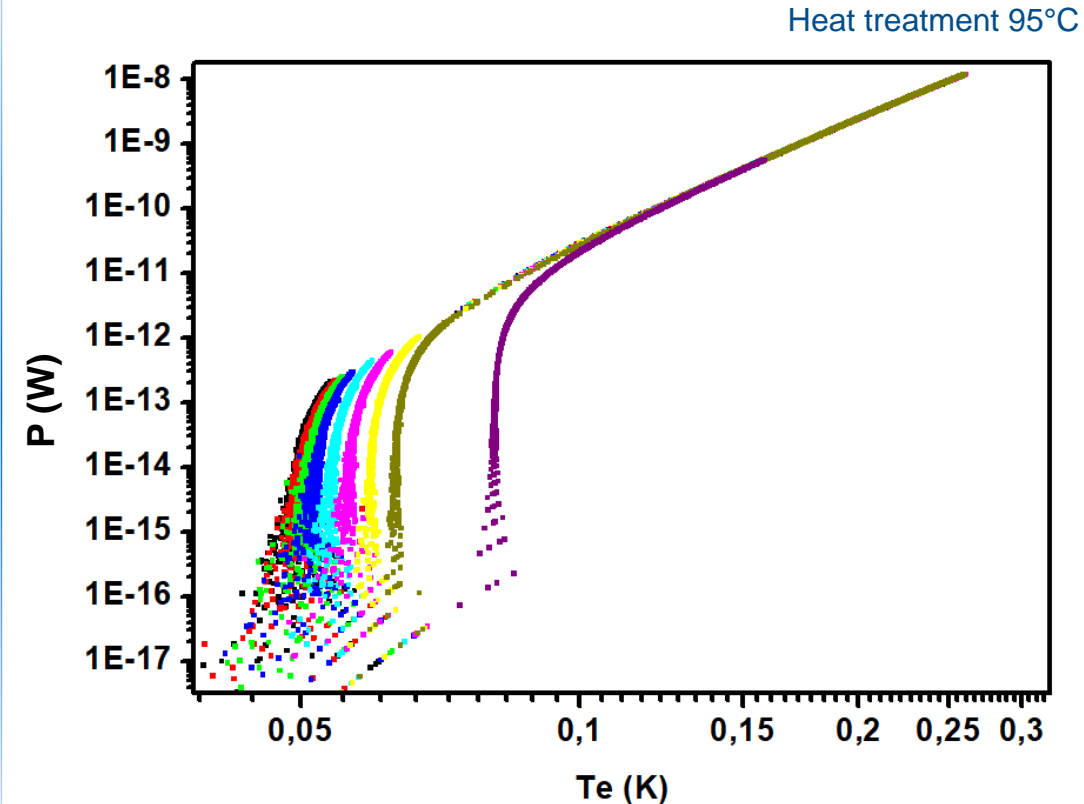
✓ **Voltage at which the current jumps**

$$V_c^2 = \frac{g_{e-ph} R_0 \beta T_0^\beta e^{\beta+1}}{(\beta + 1)^{\beta+1}}$$

McArdle and Lerner Scientific Reports 11 24293 2021



See also V. Kravtsov's talk (exptl value of g_{e-ph} larger than predicted)



I(V) curves

Comparison with heat balance equation

✓ Heat balance equation

$$P = g_{e-ph} (T_e^\beta - T_{ph}^\beta)$$

✓ Activated transport

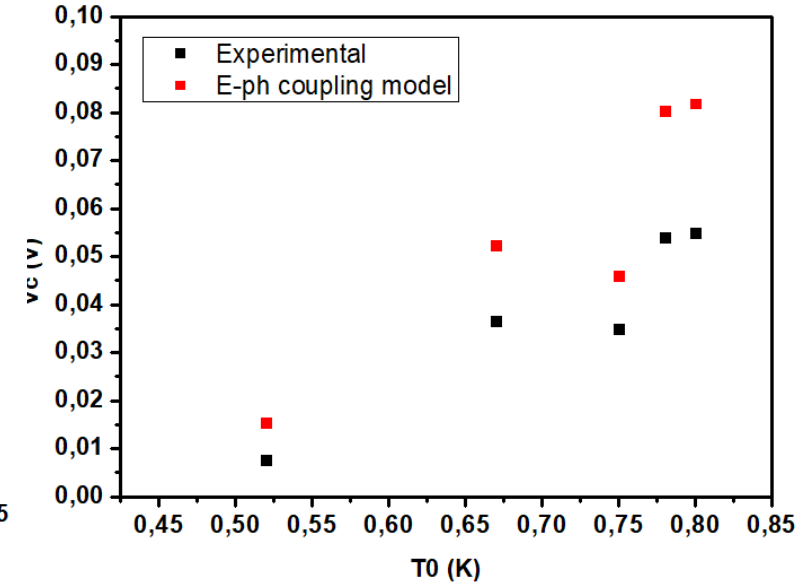
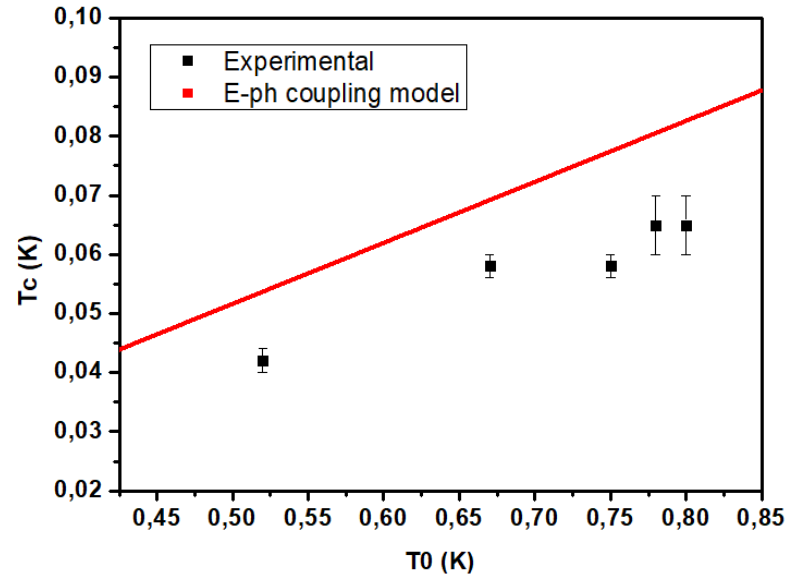
$$R = R_0 e^{T_0/T_e}$$

✓ Maximum T_{ph} for bistability

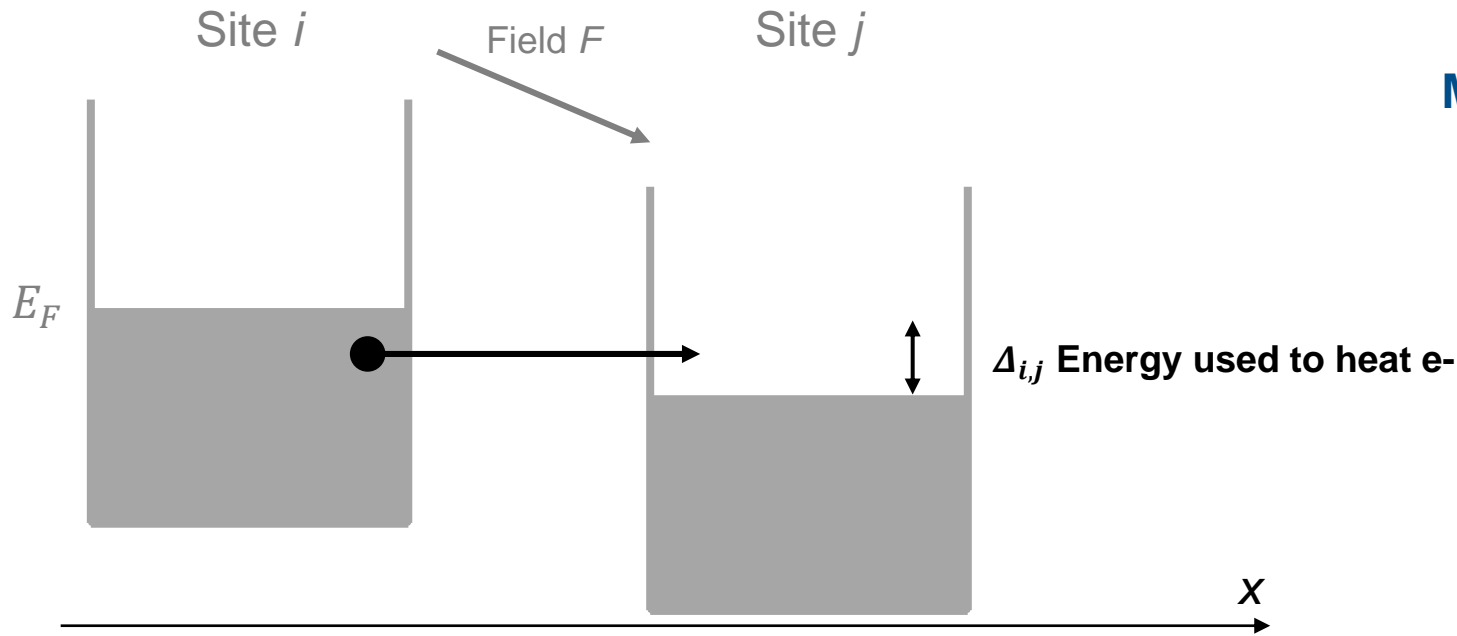
$$T_c = (\beta + 1) \frac{\beta+1}{\beta} T_0$$

✓ Voltage at which the current jumps

$$V_c^2 = \frac{g_{e-ph} R_0 \beta T_0^\beta e^{\beta+1}}{(\beta + 1)^{\beta+1}}$$



- ✓ Qualitatively explains the features
- ✓ Needs to explain the disappearance of current jumps

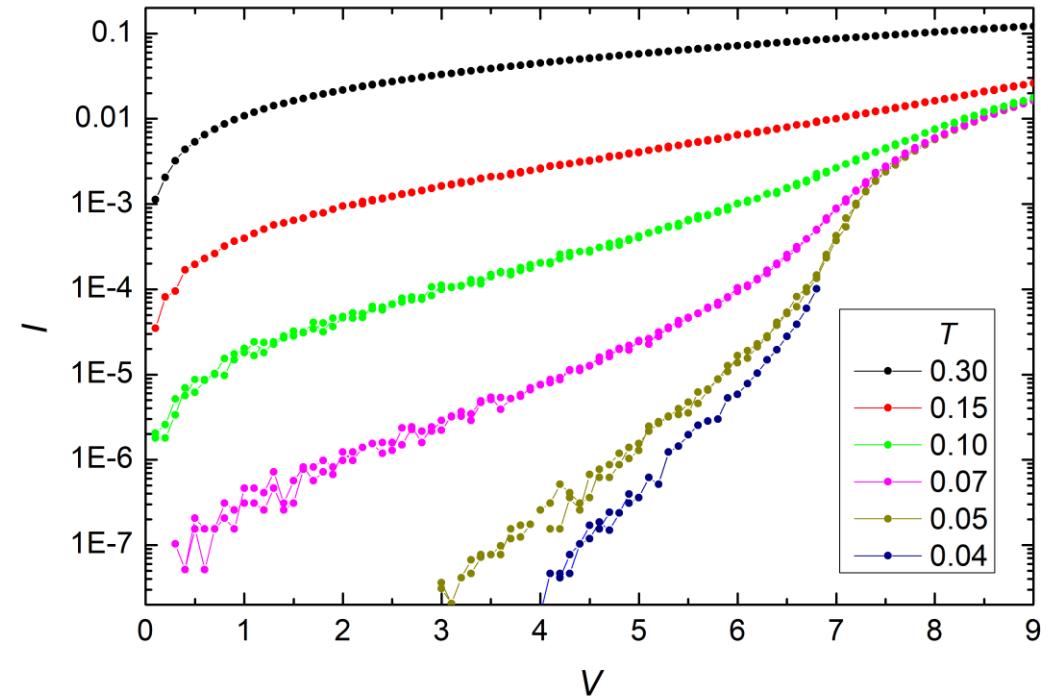
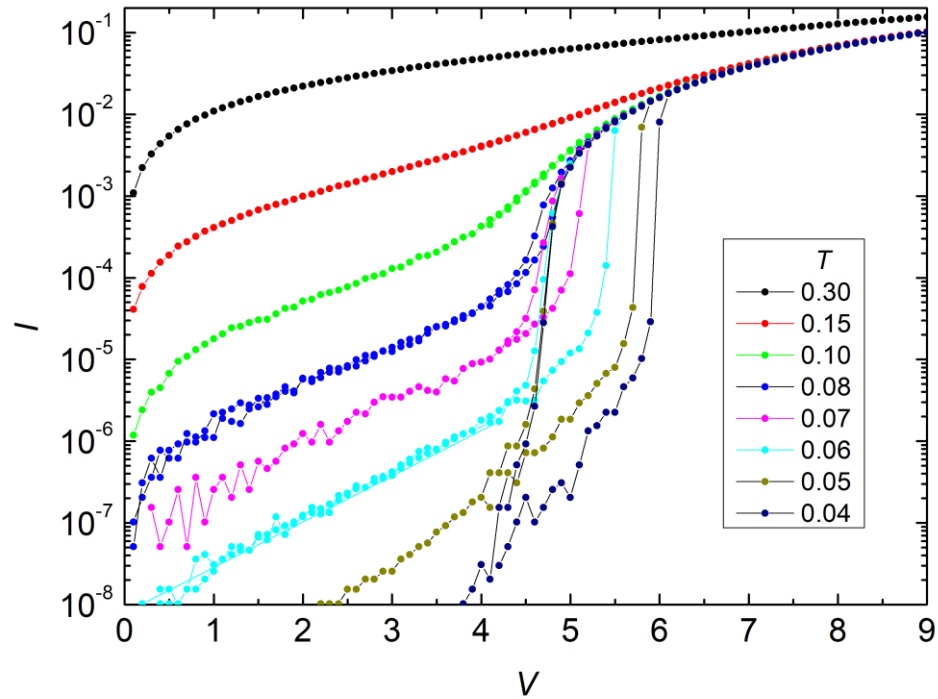


Monte Carlo simulations

- ✓ Metallic grains
- ✓ No interaction between grains
- ✓ Coulomb interactions effect:
 - ✓ Coulomb blockade (activated transport)
 - ✓ Ensures common T_e for all grains
- ✓ Phononless transport
- ✓ Phonons involved in dissipation only

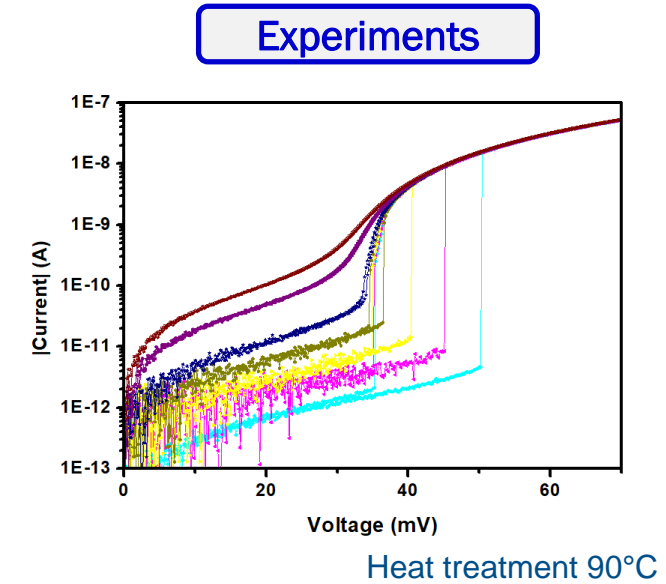
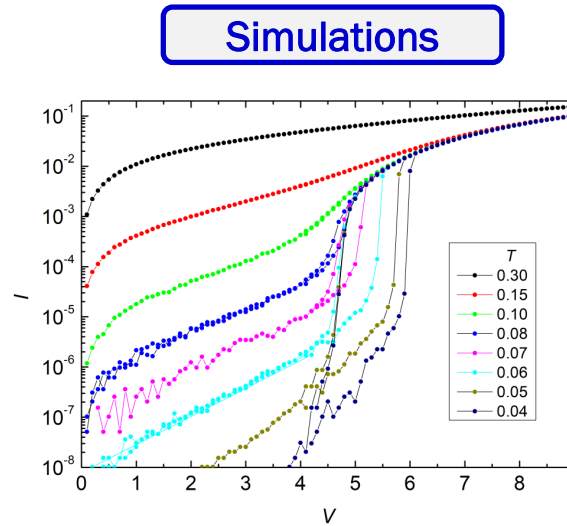
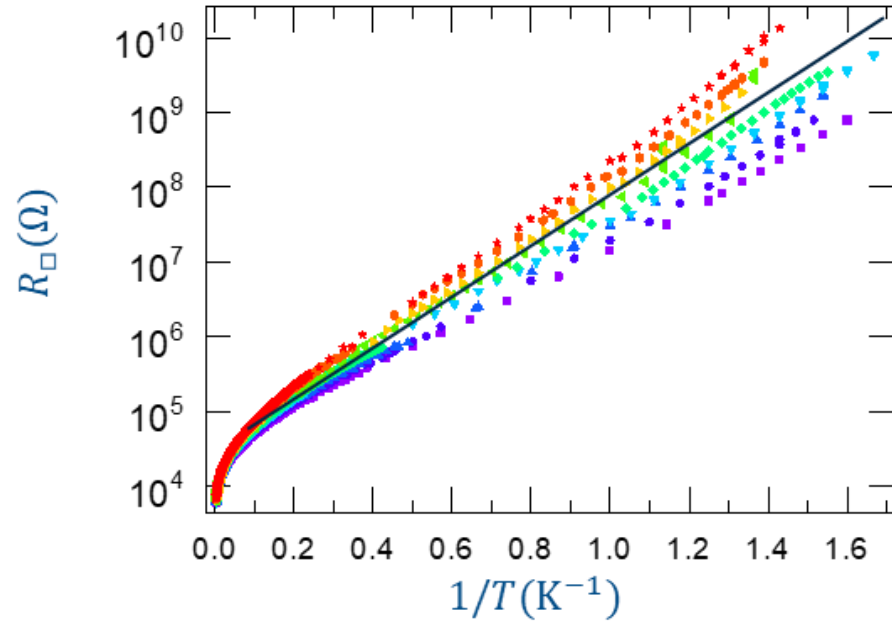
$$\Delta_{i,j} = \epsilon_j - \epsilon_i + 2E_c - (x_j - x_i)F$$

Transition rate:
$$\Gamma_{i,j} = \frac{\Delta_{i,j}}{e \frac{\Delta_{i,j}}{kT} - 1}$$



$g_{e-ph} \times 5$

Conclusion



Humbert *Nature Comm.* **12** 6733 2021

1. Activated behavior due to:
 - ✓ Hopping e-
 - ✓ High dielectric constant κ

2. Revisiting e-/ph coupling model
 - ✓ Want to compare quantitatively expmt/simulations

Thank you for your attention !

Thank you for your attention !

Outline

1. Motivation

- Superconductor-Insulator transition (SIT)

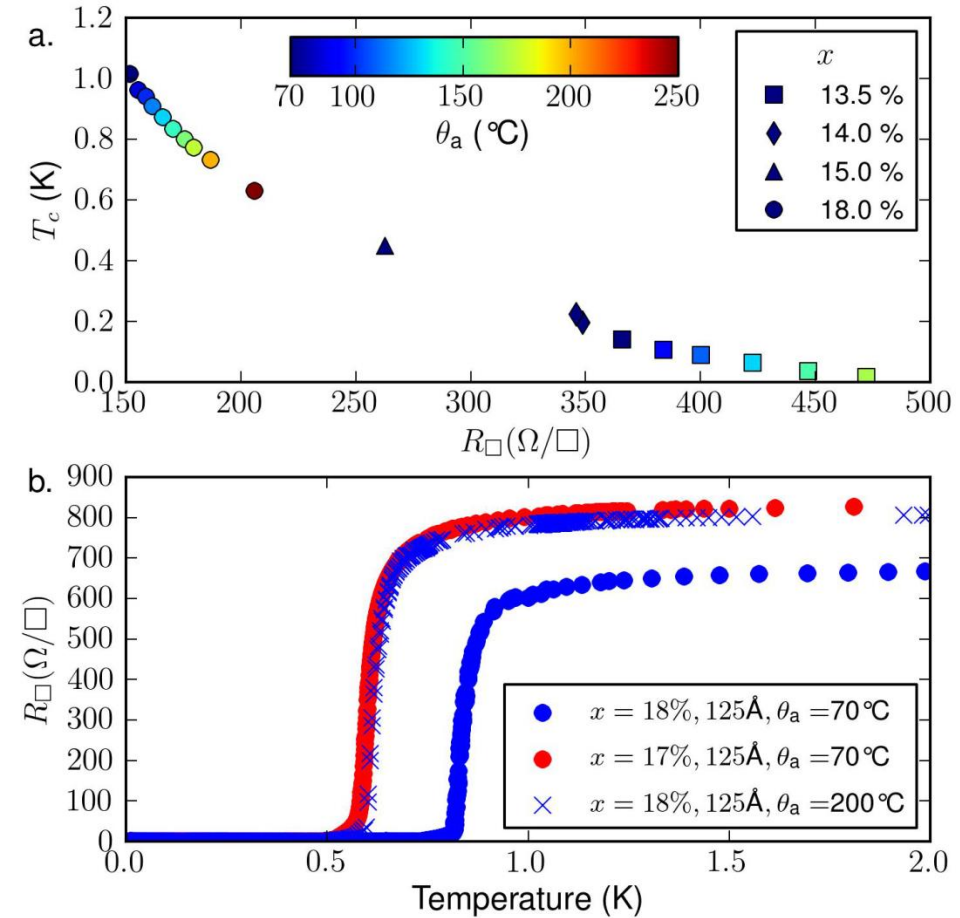
2. Activated electronic transport at the onset of the insulating regime

- a-NbSi
- 3 ways of tuning the disorder
- a-NbSi : an activated insulator

3. Electron-phonon decoupling in a-YSi films

- a-NbSi : an activated insulator
- Toward an over-activated regime close to the SIT
- Application of our model on other system

QUALIFICATION DU DÉSORDRE



50 nm samples

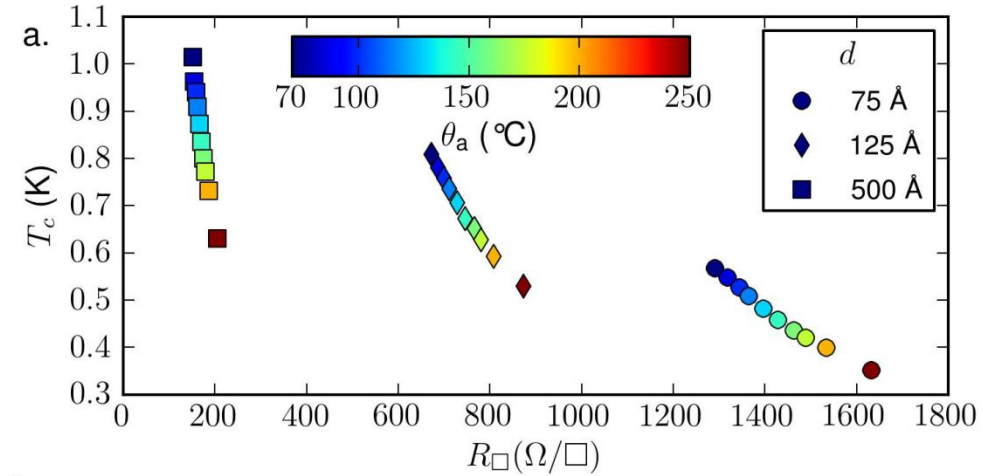
- 1 color = 1 annealing temp.
- 1 shape = 1 composition



- Same T_c evolution with the composition and the annealing

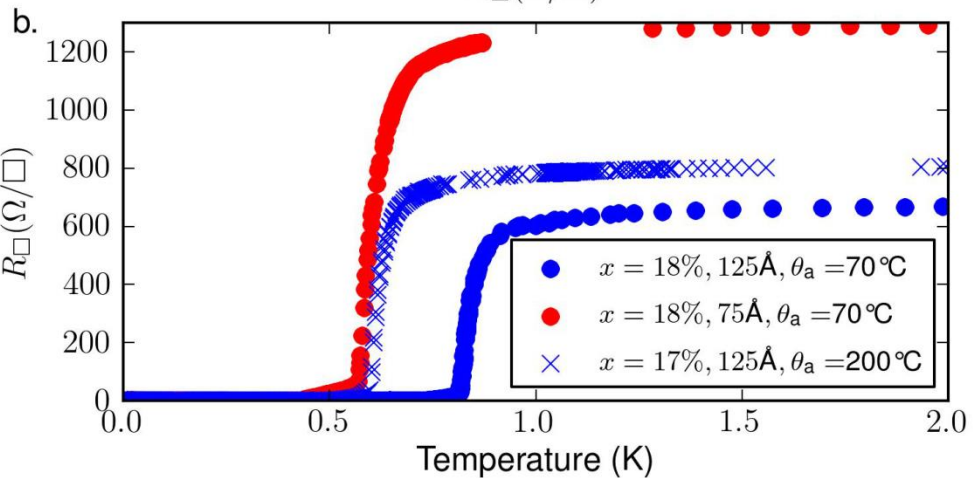
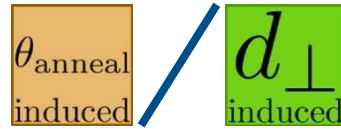
- Both affect :

$$R_{\square} \propto \frac{1}{k_F l}$$

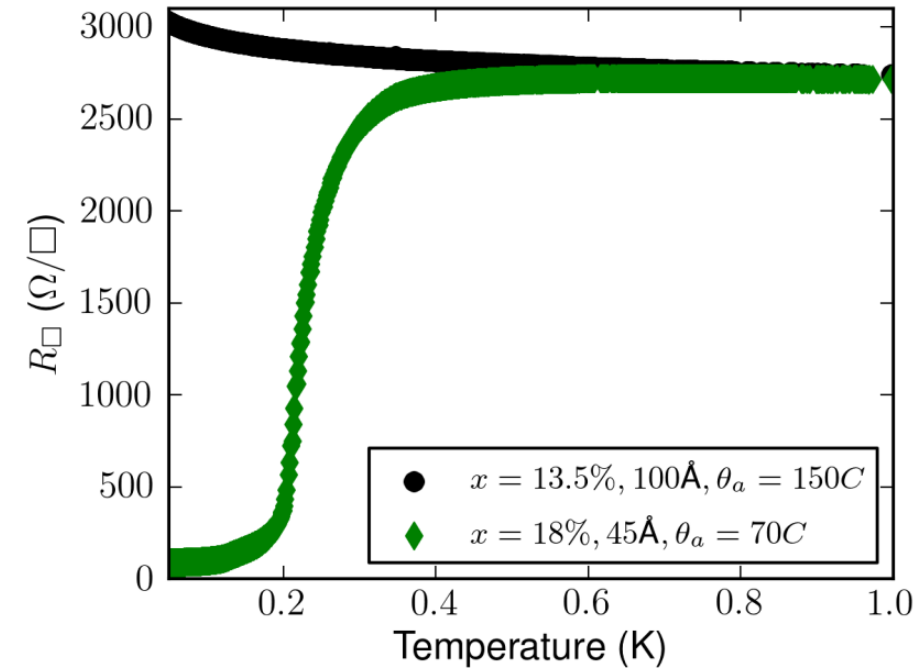


18% samples

- 1 color = 1 annealing temp.
- 1 shape = 1 thickness



- Different T_c evolution between the thickness and the annealing



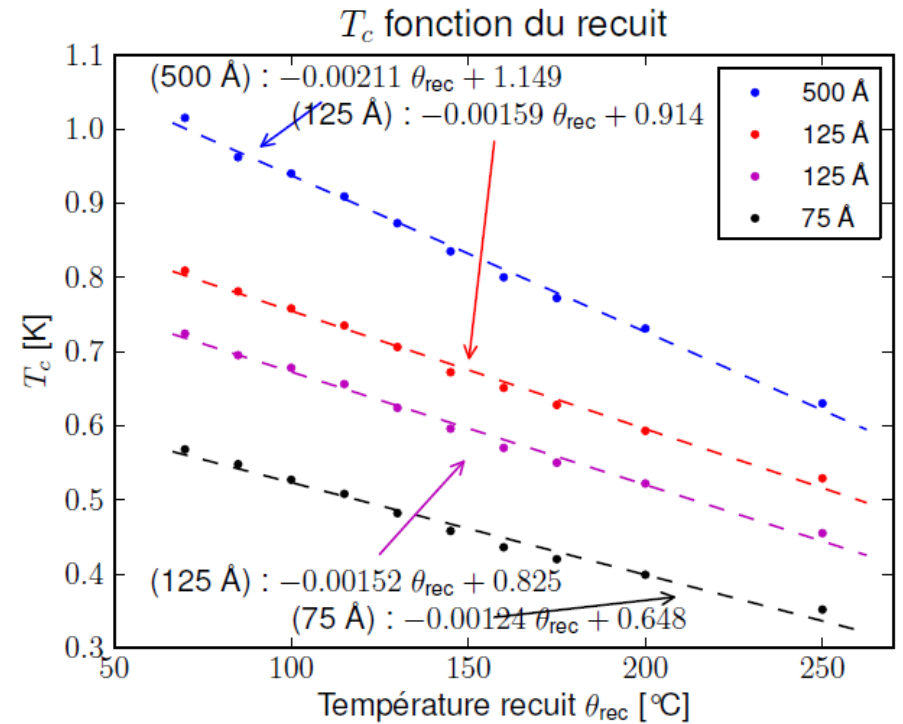
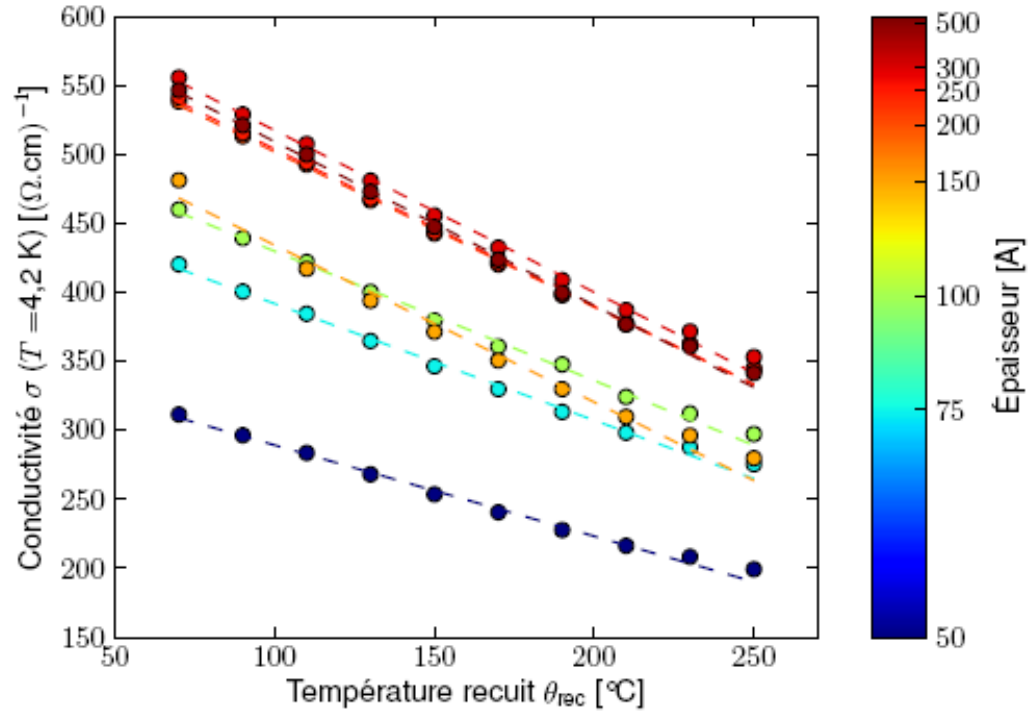
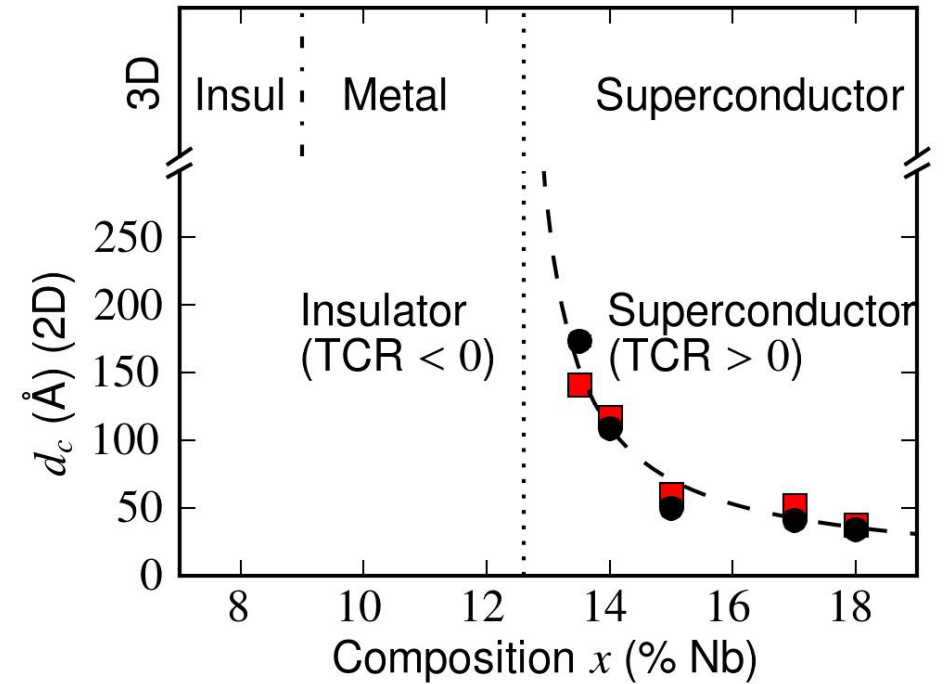
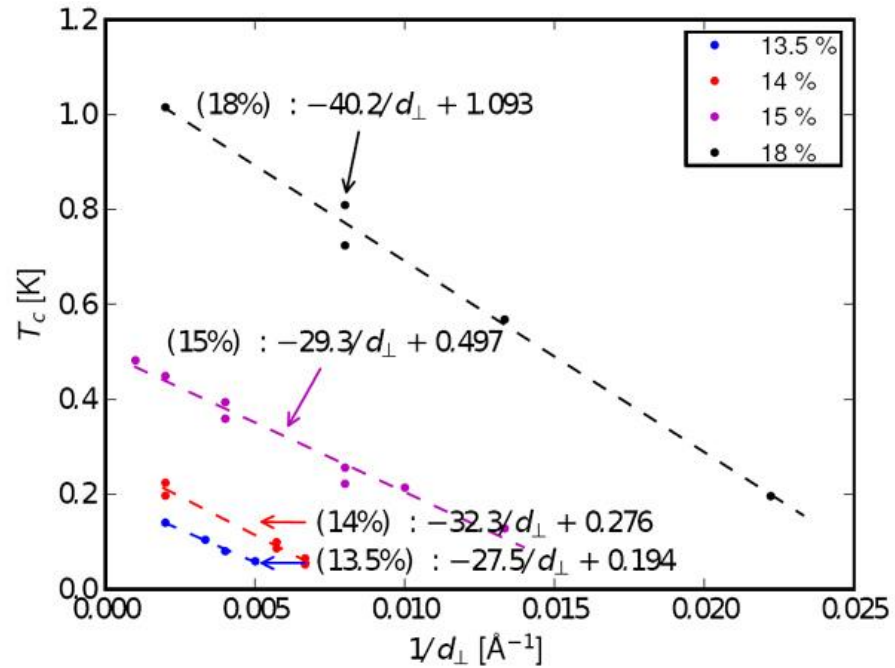


FIGURE 4.28 – Évolution des T_c en fonction du recuit. Les courbes en pointillées correspondent aux régressions linéaires, dont les valeurs sont indiquées dans la figure.

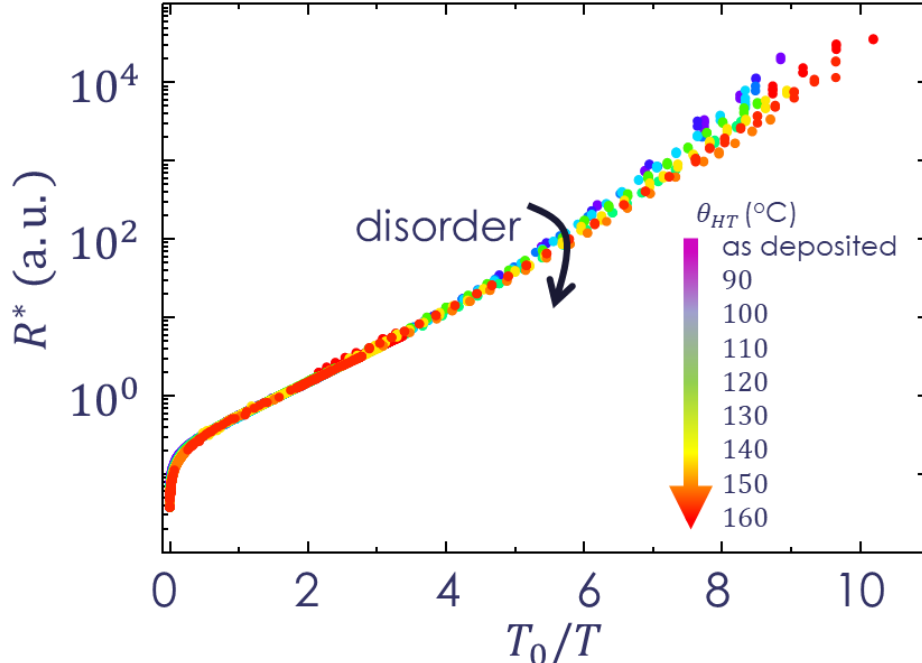
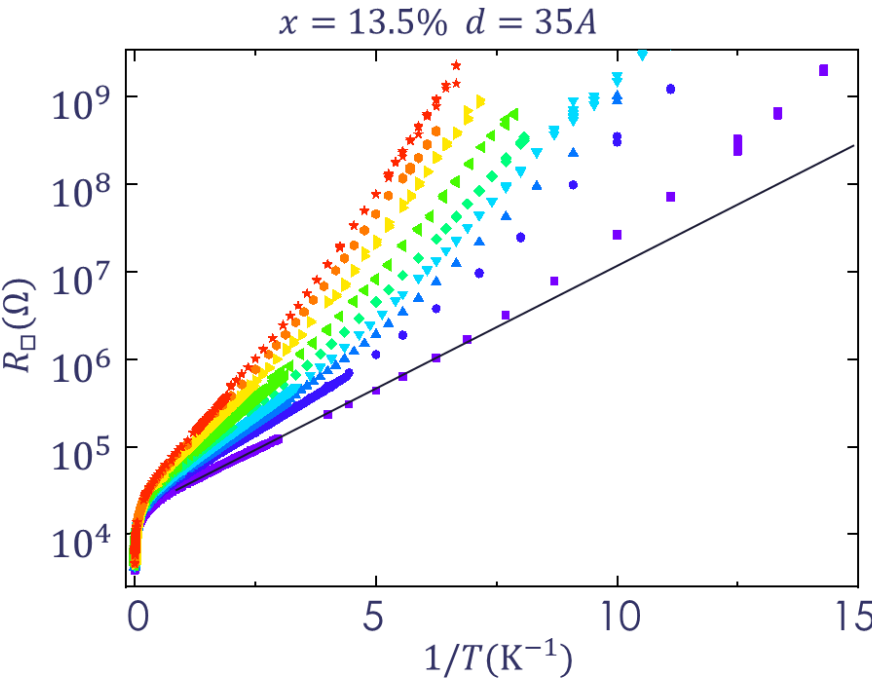


- The 2D SIT connects with the 3D MIT
- Divergence of d_c

OVERACTIVATED REGIME

Towards a stronger insulator

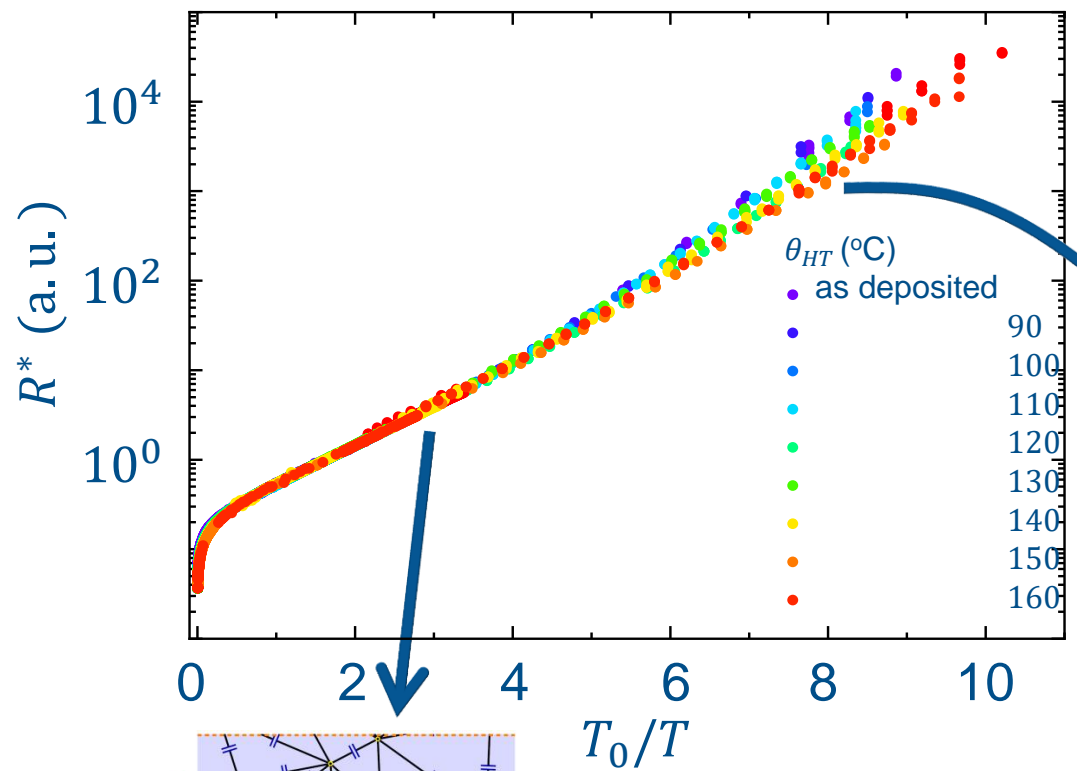
Over-activated law at low temperature



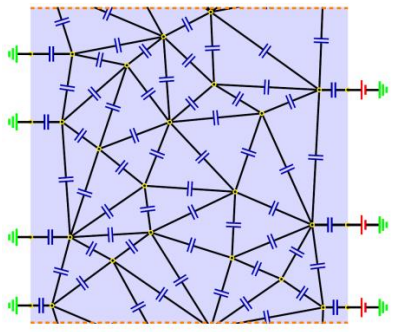
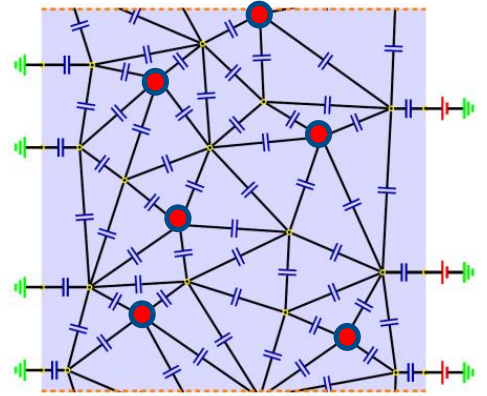
Scaling of the resistance does not work at low temperature

Over-activated regime

Influence of local superconductivity?



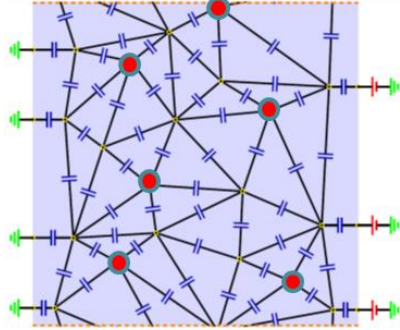
Crossing temperature $\sim T_c$ of the grains



- Non superconducting material
- Superconductor

Over-activated regime

Numerical simulations

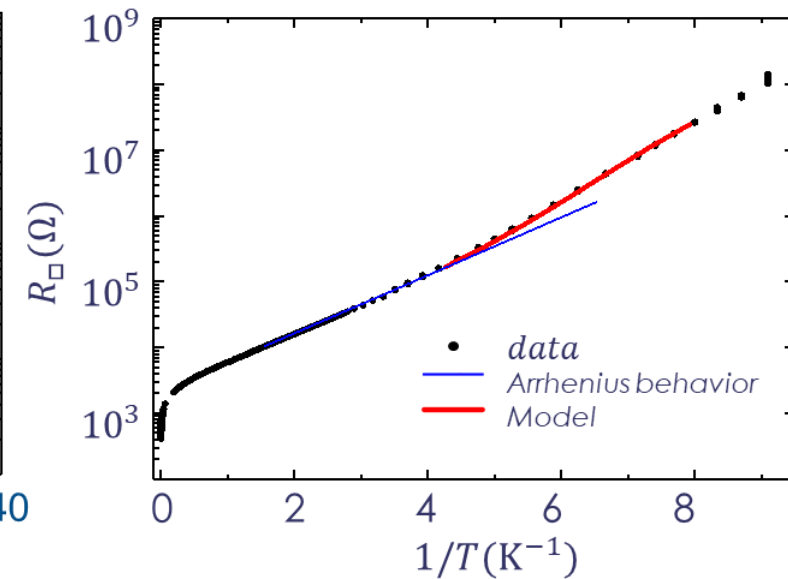
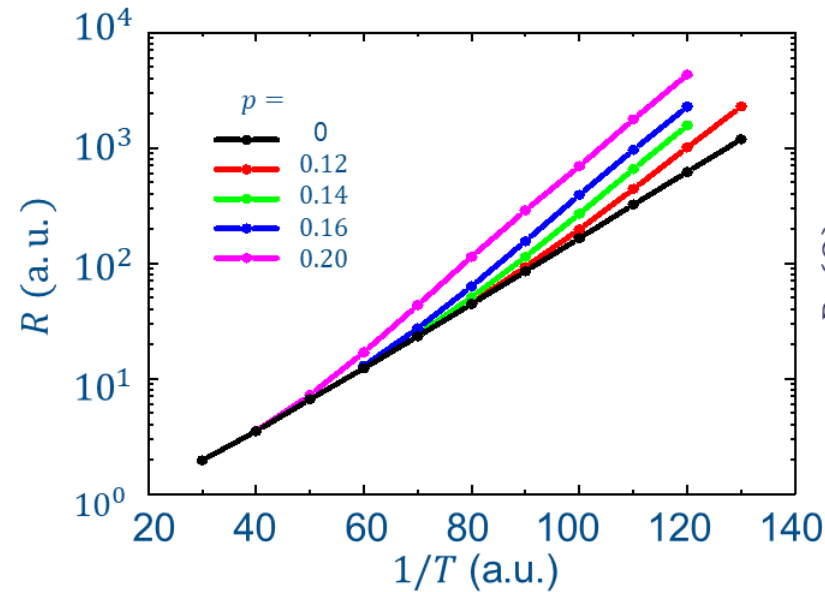


p = proportion of superconducting grains

$$T_{cross} = p T_0$$

Disorder increases (move further from SIT)

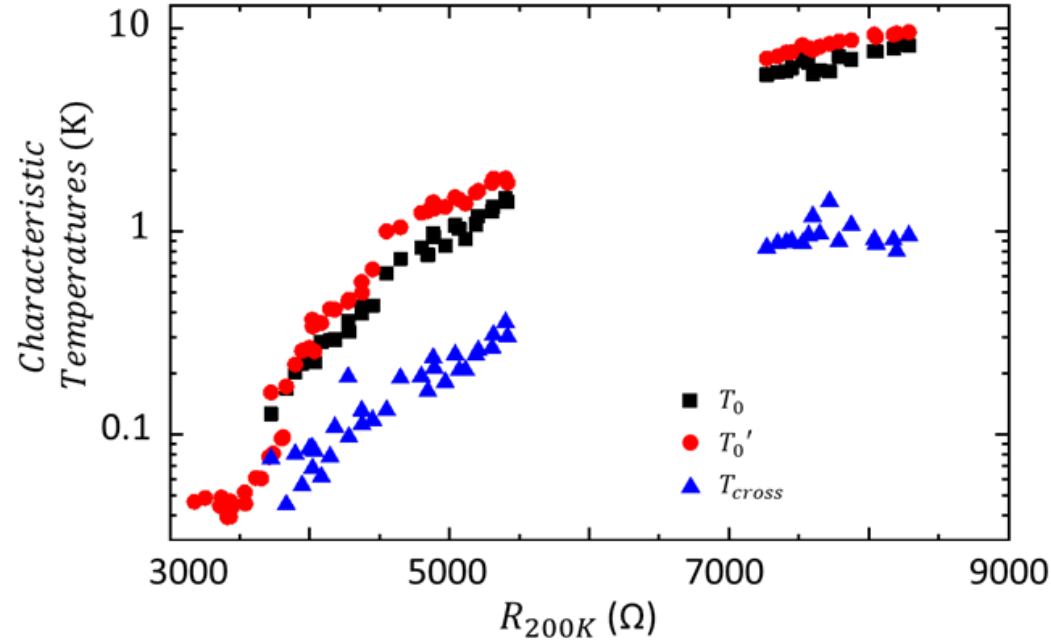
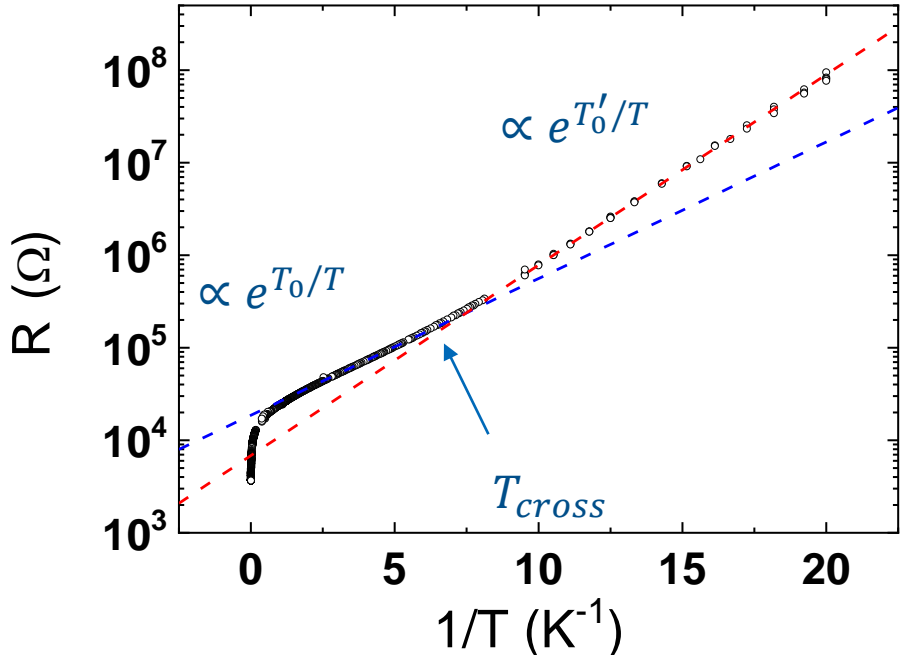
- Less superconducting puddles
- Less deviations from simple $R \sim e^{T_0/T}$
- crossover temperature decreases



Excellent agreement with expmts!

Over-activated regime

Numerical simulations



Electron hopping between grains

- T_0 activation energy at moderate temperatures
- T'_0 activation energy at the lowest temperatures
- T_{cross} crossover temperature

$$E'_0 = E_0 + c \Delta(T)$$

$$E'_0(T = 0) = E_0 + c \Delta_0$$

$$\sim E_0 + 2 c k_B T_c$$

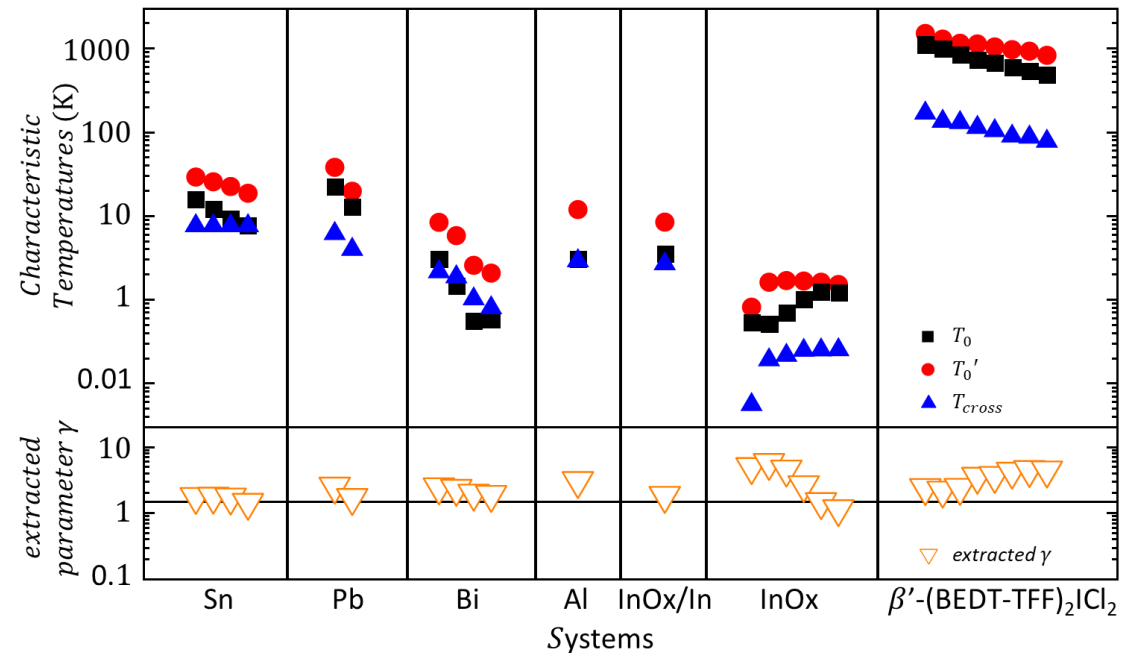
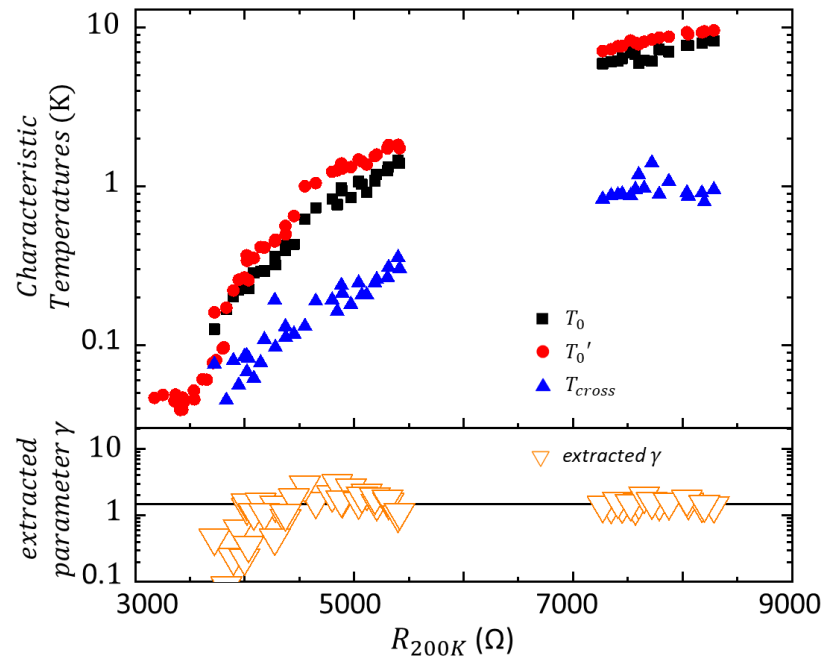
$$T'_0(T=0) = T_0 + \gamma T_{cross}$$

Monte-Carlo simulation

$$T'_0(T=0) = T_0 + 1.8 T_{cross}$$

Over-activated regime

Numerical simulations



$$T_0' = T_0 + \gamma T_{cross}$$

with $\gamma \sim \Delta_0/k_B T_c$

Monte-Carlo simulation

$$\gamma = 1.8$$

Sources

Sn, Pb : Dynes *PRL* **40** 479 (1978)

Bi, Al : Parendo *PRB* 100508 (2007)

InO_x/In : Kim *PRB* **46**(18) 11709 (1992)

InO_x : Dan Shahar (shared data)

β' -(BEDT-TFF)₂ICl₂ : Tajima *EPL* **83** 27008 (2008)

E-PH COUPLING

I(V) curves

Even larger disorder

✓ **Heat balance equation**

$$P = g_{e-ph} \left(T_e^\beta - T_{ph}^\beta \right)$$

✓ **Activated transport**

$$R = R_0 e^{T_0/T_e}$$

✓ **Maximum T_{ph} for bistability**

$$T_c = (\beta + 1)^{\frac{\beta+1}{\beta}} T_0$$

✓ **Voltage at which the current jumps**

$$V_c^2 = \frac{g_{e-ph} R_0 \beta T_0^\beta e^{\beta+1}}{(\beta + 1)^{\beta+1}}$$

